TSG RAN Meeting #17 **RP-020489**
Biarritz, France, 3 - 6 September, 2002

Title **CRs (Rel-5) to TS 25.142**
Source **TSG RAN WG4**
Agenda Item **7.4.5**

RAN4 Tdoc	Spec	CR	R	Cat	Rel	Curr Ver	Title	Work Item
R4-021316	25.142	138	1	F	Rel-5	5.1.0	General corrections to TS25.142	TEI5
R4-021216	25.142	141		F	Rel-5	5.1.0	Correction of Node B test configurations	TEI5
R4-021217	25.142	142		F	Rel-5	5.1.0	Correction of QPSK EVM/PCDE test for 1.28 Mcps TDD option.	LCRTDD-RF

3GPP TSR RAN WG4 Meeting #24 **R4-021316**

Helsinki, Finland 12 - 16 August 2002

CR-Form-v7

CHANGE REQUEST

⌘ **25.142** **CR** **138** ⌘ **rev** **1** ⌘ Current version: **5.1.0** ⌘

*For **HELP** on using this form, see bottom of this page or look at the pop-up text over the ⌘ symbols.*

Proposed change affects: UICC apps⌘ ☐ ME ☐ Radio Access Network ☒ Core Network ☐

Title:	⌘	General corrections to TS25.142.
Source:	⌘	RAN WG4
Work item code:	⌘	TEI5
Date:	⌘	21/08/2002
Category:	⌘	**F**
Release:	⌘	Rel-5

Use one of the following categories:
F *(correction)*
A *(corresponds to a correction in an earlier release)*
B *(addition of feature),*
C *(functional modification of feature)*
D *(editorial modification)*
Detailed explanations of the above categories can be found in 3GPP TR 21.900.

Use one of the following releases:

2	*(GSM Phase 2)*
R96	*(Release 1996)*
R97	*(Release 1997)*
R98	*(Release 1998)*
R99	*(Release 1999)*
Rel-4	*(Release 4)*
Rel-5	*(Release 5)*
Rel-6	*(Release 6)*

Reason for change: ⌘ The present CR aims at correcting small issues and typos within 25.142:

1- Ancillary definition in section 5.14.4 should be in 3.1.

2- The procedure for maximum output power test and the initial condition for minimum output power test were not corrected according to the new power definitions agreed by RAN#16 in RP-020287 CR121.

3- Confusion exists between receive and transmit timeslot in some test procedures for 1.28 Mcps TDD option (maximum output power, power control step, power control dynamic range, minimum output power).

4- In PCCPCH power test, the test environment is normal and extreme in ''test purpose description'' section and normal in ''general test conditions'' section.

5- At RAN#16, new ACLR requirements defined as absolute adjacent channel leakage powers were introduced as a conclusion of the base station WI (CR 119). In the meanwhile, new power definitions were agreed in CR113 and CR115 for TS25.105. In order to have independent CRs, the power definitions used for the new ACLR requirement were based on the old status of the specification.
(Note: This correction reflects the correction proposed in CR123 for TS25.105)

Summary of change: ⌘ 1- Ancillary definition moved from 5.14.4 to section 3.1.

2- Alignment with the new power definitions agreed in RAN#16 in RP-020287 CR121.

		3-Typos in some test procedures are corrected 4-PCCPCH test environmemt is corrected to normal condiftions. 5- Power description used for absolute ACLR requirement is aligned with the general power definition wording.
Consequences if not approved:	⌘	1- Ancillary definition position remains unpractical. 2- Reference to a old power definition remains. 3-Test procedures remain unclear. 4- PCCPCH power test environment conditions remain unclear. 5- Same as 2.

Clauses affected:	⌘	3.1, 5.14, 6.2, 6.4.2, 6.4.3, 6.4.4, 6.4.5 .6.6.2.2			
		Y	**N**		
Other specs Affected:	⌘		**X**	Other core specifications	⌘
			X	Test specifications	
			X	O&M Specifications	
Other comments:	⌘				

How to create CRs using this form:
Comprehensive information and tips about how to create CRs can be found at http://www.3gpp.org/specs/CR.htm. Below is a brief summary:

1) Fill out the above form. The symbols above marked ⌘ contain pop-up help information about the field that they are closest to.

2) Obtain the latest version for the release of the specification to which the change is proposed. Use the MS Word "revision marks" feature (also known as "track changes") when making the changes. All 3GPP specifications can be downloaded from the 3GPP server under ftp://ftp.3gpp.org/specs/ For the latest version, look for the directory name with the latest date e.g. 2001-03 contains the specifications resulting from the March 2001 TSG meetings.

3) With "track changes" disabled, paste the entire CR form (use CTRL-A to select it) into the specification just in front of the clause containing the first piece of changed text. Delete those parts of the specification which are not relevant to the change request.

3.1 ~~3.1~~ Definitions

Ancillary RF amplifier: a piece of equipment, which when connected by RF coaxial cables to the BS, has the primary function to provide amplification between the transmit and/or receive antenna connector of a BS and an antenna without requiring any control signal to fulfil its amplifying function.

Power Spectral Density: The units of Power Spectral Density (PSD) are extensively used in this document. PSD is a function of power versus frequency and when integrated across a given bandwidth, the function represents the mean power in such a bandwidth. When the mean power is normalised to (divided by) the chip-rate it represents the mean energy per chip. Some signals are directly defined in terms of energy per chip, (DPCH_Ec, Ec, and P-CCPCH_Ec) and others defined in terms of PSD (Io, Ioc, Ior and $\hat{I}$or). There also exist quantities that are a ratio of energy per chip to PSD (DPCH_Ec/Ior, Ec/Ior etc.). This is the common practice of relating energy magnitudes in communication systems.

It can be seen that if both energy magnitudes in the ratio are divided by time, the ratio is converted from an energy ratio to a power ratio, which is more useful from a measurement point of view. It follows that an energy per chip of X dBm/3.84 MHz can be expressed as a mean power per chip of X dBm. Similarly, a signal PSD of Y dBm/3.84 MHz can be expressed as a signal power of Y dBm.

Mean power: When applied to a CDMA modulated signal this is the power (transmitted or received) in a bandwidth of at least (1+ α) times the chip rate of the radio access mode. The period of measurement shall be a transmit timeslot excluding the guard period unless otherwise stated.

NOTE: The roll-off factor α is defined in section 6.8.1.

RRC filtered mean power: The mean power as measured through a root raised cosine filter with roll-off factor α and a bandwidth equal to the chip rate of the radio access mode.

NOTE: The RRC filtered mean power of a perfectly modulated CDMA signal is 0.246 dB lower than the mean power of the same signal.

Code domain power: That part of the mean power which correlates with a particular (OVSF) code channel. The sum of all powers in the code domain equals the mean power in a bandwidth of (1+ α) times the chip rate of the radio access mode.

Output power: The mean power of one carrier of the base station, delivered to a load with resistance equal to the nominal load impedance of the transmitter.

Maximum output power: The mean power level per carrier of the base station measured at the antenna connector in a specified reference condition. The period of measurement shall be a transmit timeslot excluding the guard period.

Rated output power: Rated output power of the base station is the mean power level per carrier that the manufacturer has declared to be available at the antenna connector.

---NEXT SECTION---

5.14.4 Ancillary RF amplifiers

~~**Ancillary RF amplifier:** a piece of equipment, which when connected by RF coaxial cables to the BS, has the primary function to provide amplification between the transmit and/or receive antenna connector of a BS and an antenna without requiring any control signal to fulfil its amplifying function.~~

The requirements of this TS shall be met with the ancillary RF amplifier fitted. At tests according to clause 6 and 7 for TX and RX respectively, the ancillary amplifier is connected to the BS by a connecting network (including any cable(s), attenuator(s), etc.) with applicable loss to make sure the appropriate operating conditions of the ancillary amplifier and the BS. The applicable connecting network loss range is declared by the manufacturer. Other characteristics and the temperature dependence of the attenuation of the connecting network are neglected. The actual attenuation value of the connecting network is chosen for each test as one of the applicable extreme values. The lowest value is used unless otherwise stated.

Sufficient tests should be repeated with the ancillary amplifier fitted and, if it is optional, without the ancillary RF amplifier to verify that the BS meets the requirements of this TS in both cases.

---NEXT SECTION---

6.2 Maximum output power

6.2.1 Definition and applicability

Maximum output power (Pmax) and rated output power (PRAT) are defined in subclause 3.1.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.2.2 Minimum Requirements

In normal conditions, the base station maximum output power shall remain within +2 dB and –2 dB of the manufacturer's rated output power.

In extreme conditions, the base station maximum output power shall remain within +2,5 dB and –2,5 dB of the manufacturer's rated output power.

In certain regions, the minimum requirement for normal conditions may apply also for some conditions outside the ranges defined for the Normal test environment in subclause 5.9.1.

The normative reference for this requirement is TS 25.105 [1] subclause 6.2.1.1.

6.2.3 Test purpose

The test purpose is to verify the accuracy of the maximum output power across the frequency range and under normal and extreme conditions for all transmitters in the BS.

6.2.4 Method of test

6.2.4.1 Initial conditions

6.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

In addition, on one UARFCN only, the test shall be performed under extreme power supply as defined in subclause 5.9.4.

NOTE: Tests under extreme power supply also test extreme temperature.

6.2.4.1.1 3,84 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the power measuring equipment to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.1.

Table 6.1: Parameters of the transmitted signal for maximum output power test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
BS output power setting	PRAT
Number of DPCH in each active TS	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.2.4.1.2 1,28 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the power measuring equipment to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.1A.

Table 6.1A: Parameters of the transmitted signal for maximum output power test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
BS output power setting	PRAT
Number of DPCH in each active TS	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.2.4.2 Procedure

6.2.4.2.1 3,84 Mcps TDD option

(1) Measure ~~thermal~~ the output power of the BS ~~output~~ signal. ~~over the 2464 active chips of an even time slot TS i (this excludes the guard periods), and with a measurement bandwidth of at least 5 MHz.~~

(2) Run step (1) for RF channels Low / Mid / High.

6.2.4.2.2 1,28 Mcps TDD option

(1) Measure ~~thermal~~ the output power of the BS ~~output~~ signal. ~~over the 848 active chips of an even time slot TS i (this excludes the guard periods), and with a measurement bandwidth of at least 1,6 MHz~~.

(2) Run step (1) for RF channels Low / Mid / High.

6.2.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

In normal conditions, the measured output power, derived according to subclause 6.2.4.2, shall remain within +2,7 dB and –2,7 dB of the manufacturer's rated output power.

In extreme conditions, the measured output power, derived according to subclause 6.2.4.2, shall remain within +3,2 dB and –3,2 dB of the manufacturer's rated output power.

---NEXT SECTION---

6.4 Output power dynamics

6.4.1 Inner loop power control

Inner loop power control is the ability of the BS transmitter to adjust its code domain power in response to the UL received signal.

For inner loop correction on the Downlink Channel, the base station adjusts the code domain power of a power controlled CCTrCH in response to each valid power control bit received from the UE on the Uplink Traffic Channel based on the mapping of the TPC bits in uplink CCTrCH to downlink CCTrCH. Inner loop control is based on SIR measurements at the UE receiver, and the corresponding TPC commands are generated by the UE.

6.4.2 Power control steps

6.4.2.1 Definition and applicability

The power control step is the step change in the DL code domain power in response to a TPC message from the UE.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.2.2 Minimum Requirements

The power control step sizes in the DL shall be 1 dB, 2 dB and 3 dB.

The tolerance of the code domain power and the greatest average rate of change in code domain power due to the power control step shall be within the range shown in Table 6.3.

Table 6.3: Power control step size tolerance

Step size	Tolerance	Range of average rate of change in code domain power per 10 steps	
		Minimum	maximum
1dB	± 0,5 dB	± 8 dB	± 12 dB
2dB	± 0,75 dB	± 16 dB	± 24 dB
3dB	± 1 dB	± 24 dB	± 36 dB

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.2.1.

6.4.2.3 Test purpose

The DL power control is applied to adjust the BS code domain power to a value that is sufficiently high to generate a SIR at the UE receiver equal to the target SIR, while limiting the intercell interference.

The test purpose is to verify the ability of the BS to interpret received TPC commands in a correct way and to adjust its code domain power according to these commands with the specified accuracy.

6.4.2.4 Method of test

6.4.2.4.1 Initial conditions

6.4.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.2.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Disable closed loop power control in the BS under test.

(3) Set the initial parameters of the BS transmitted signal according to table 6.4.

(4) Operate the BS in such a mode that it is able to interpret received TPC commands.

(5) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.4: Initial parameters of the BS transmitted signal for power control steps test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Number of DPCH in each active TS	1
DPCH power	Minimum
Data content of DPCH	real life (sufficient irregular)

6.4.2.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Disable closed loop power control in the BS under test.

(3) Set the initial parameters of the BS transmitted signal according to table 6.4A.

(4) Operate the BS in such a mode that it is able to interpret received TPC commands.

(5) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.4A: Initial parameters of the BS transmitted signal for power control steps test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0, 4,5,6; receive, if i is 1,2,3.
Number of DPCH in each active TS	1
DPCH power	Minimun
Data content of DPCH	real life (sufficient irregular)

6.4.2.4.2 Procedure

6.4.2.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH. This sequence shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS) and shall consist of a series of TPC commands with content "Increase Tx power", followed by a series of TPC commands with content "Decrease Tx power". Each of these series should be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum and its minimum, respectively.

(3) Measure the code domain power of the active DPCH over the 2464 active chips of each even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Based on the measurement made in step (3), calculate the power control step sizes and the average rate of change per 10 steps.

(5) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (4).

6.4.2.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH. This sequence shall be transmitted to the BS within the ~~odd time slots TS i (~~receive time slots TS i of the BS~~)~~ and shall consist of a series of TPC commands with content "Increase Tx power", followed by a series of TPC commands with content "Decrease Tx power". Each of these series should be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum and its minimum, respectively.

(3) Measure the code domain power of the active DPCH over the 848 active chips of each transmit~~even~~ time slot TS i of the BS (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Based on the measurement made in step (3), calculate the power control step sizes and the average rate of change per 10 steps.

(5) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (4).

6.4.2.5 Test Requirements

NOTE: If the Test Requirements below differ from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.4.2.5.1 3,84 Mcps TDD option

For all measurements, the tolerance of the power control step sizes and the average rate of change per 10 steps shall be within the limits given in Table 6.5.

Table 6.5: Test Requirements for power control step size tolerance

Step size	Single step tolerance	Range of average rate of change in code domain power per 10 steps	
		Minimum	maximum
1dB	± 0,6 dB	± 7,7 dB	± 12,3 dB
2dB	± 0,85 dB	± 15,7 dB	± 24,3 dB
3dB	± 1,1 dB	± 23,7 dB	± 36,3 dB

In case, the power control step size is set to 3 dB, the number of power control steps feasible within the power control dynamic range of the BS under test may be less than 10. In this case, the evaluation of the average rate of change in code domain power shall be based on the number of power control steps actually feasible, and the permitted range of average rate of change shall be reduced compared to the values given in table 6.5 in proportion to the ratio (number of power control steps actually feasible /10).

EXAMPLE: If the number of power control steps actually feasible is 9, the minimum and maximum value of the range of average rate of change in code domain power are given by ±21,3 dB and ±32,7 dB, respectively.

6.4.2.5.2 1,28 Mcps TDD option

For all measurements, the tolerance of the power control step sizes and the average rate of change per 10 steps shall be within the limits given in Table 6.5.

In case, the power control step size is set to 3 dB, the number of power control steps feasible within the power control dynamic range of the BS under test may be less than 10. In this case, the evaluation of the average rate of change in code domain power shall be based on the number of power control steps actually feasible, and the permitted range of average rate of change shall be reduced compared to the values given in table 6.5 in proportion to the ratio (number of power control steps actually feasible /10).

EXAMPLE: If the number of power control steps actually feasible is 9, the minimum and maximum value of the range of average rate of change in code domain power are given by 21,6 dB and 32,4 dB, respectively.

6.4.3 Power control dynamic range

6.4.3.1 Definition and applicability

The power control dynamic range is the difference between the maximum and the minimum code domain power of one power controlled code channel for a specified reference condition.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.3.2 Minimum Requirements

The DL power control dynamic range shall be greater than or equal to 30 dB.

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.3.1.

6.4.3.3 Test purpose

The test purpose is to verify the ability of the BS to control the code domain power of a single code signal over the specified dynamic range.

6.4.3.4 Method of test

6.4.3.4.1 Initial conditions

6.4.3.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.3.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.6.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;

- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.6: Parameters of the BS transmitted signal for power control dynamic range test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Number of DPCH in each active TS	1
Data content of DPCH	real life (sufficient irregular)

6.4.3.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.6A.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;

- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.6A: Parameters of the BS transmitted signal for power control dynamic range test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0, 4,5,6; receive, if i is 1,2,3.
Number of DPCH in each active TS	1
Data content of DPCH	real life (sufficient irregular)

6.4.3.4.2 Procedure

6.4.3.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Increase Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(3) Measure the code domain power of the active DPCH over the 2464 active chips of an even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(5) Measure the code domain power of the active DPCH over the 2464 active chips of an even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(6) Determine the power control dynamic range by calculating the difference between the maximum code domain power measured in step (3) and the minimum code domain power measured in step (5).

(7) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (6).

6.4.3.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Increase Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(3) Measure the code domain power of the active DPCH over the 848 active chips of a~~n receive~~ transmit time slot TS i of the BS (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(5) Measure the code domain power of the active DPCH over the 848 active chips of a transmit~~receive~~ time slot TS i of the BS (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(6) Determine the power control dynamic range by calculating the difference between the maximum code domain power measured in step (3) and the minimum code domain power measured in step (5).

(7) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (6).

6.4.3.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The power control dynamic range derived according to subclause 6.4.3.4.2 shall be greater than or equal to 29,7 dB

6.4.4 Minimum output power

6.4.4.1 Definition and applicability

The minimum controlled output power of the BS is when the power is set to a minimum value.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.4.2 Minimum Requirements

The DL minimum output power shall be less than or equal to:

Maximum output power - 30 dB.

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.4.1.

6.4.4.3 Test purpose

The test purpose is to verify the ability of the BS to reduce its output power to a specified value.

6.4.4.4 Method of test

6.4.4.4.1 Initial conditions

6.4.4.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.4.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.7.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyse the output signal of the BS under test with respect to mean~~thermal~~ power;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.7: Parameters of the BS transmitted signal for minimum power test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Number of DPCH in each active TS	1
Data content of DPCH	real life (sufficient irregular)

6.4.4.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.7A.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyse the output signal of the BS under test with respect to mean~~thermal~~ power;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.7A: Parameters of the BS transmitted signal for minimum power test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
BS output power setting	PRAT
Number of DPCH in each active TS	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.4.4.4.2 Procedure

6.4.4.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to all active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the output power of all active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(3) Measure the power of the BS output signal over the 2464 active chips of an even time slot TS i (this excludes the guard period), and with a measurement filter that has a RRC filter response with a roll off $\alpha = 0,22$ and a bandwidth equal to the chip rate. The power is determined by calculating the RMS value of the signal samples at the measurement filter output taken at the decision points.

(4) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) and (3).

6.4.4.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to all active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the output power of all active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(3) Measure the power of the BS output signal over the 848 active chips of a ~~receive~~ time slot TS i (this excludes the guard period), and with a measurement filter that has a RRC filter response with a roll off $\alpha = 0,22$ and a bandwidth equal to the chip rate. The power is determined by calculating the RMS value of the signal samples at the measurement filter output taken at the decision points.

(4) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) and (3).

6.4.4.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

For all measurements, the minimum output power derived in step (4) of subclause 6.4.4.4.2 shall be at least 29,3 dB below the maximum output power as declared by the manufacturer; see 6.2.

6.4.5 Primary CCPCH power

6.4.5.1 Definition and applicability

Primary CCPCH power is the code domain power of the Primary Common Control Physical Channel averaged over the transmit timeslot. Primary CCPCH power is signalled on the BCH.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.5.2 Minimum Requirements

The error between the BCH-broadcast value of the Primary CCPCH power and the Primary CCPCH code domain power averaged over the timeslot shall not exceed the values in table 6.8. The error is a function of the output power averaged over the timeslot, Pout, and the manufacturer's rated output power, PRAT.

Table 6.8: Errors between Primary CCPCH power and the broadcast value

Output power in slot, dB	PCCPCH power tolerance
PRAT - 3 < Pout ≤ PRAT + 2	+/- 2,5 dB
PRAT - 6 < Pout ≤ PRAT - 3	+/- 3,5 dB
PRAT - 13 < Pout ≤ PRAT - 6	+/- 5 dB

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.5.

6.4.5.3 Test purpose

The code domain power of the Primary CCPCH received by the UE, together with the information on the Primary CCPCH nominal output power signaled on the BCH, are used by the UE for path loss estimation and adjustment of its own transmit power. Therefore, deviations of the Primary CCPCH code domain power from its nominal value are transposed by the UE into deviations from the wanted output power of the UE.

The test purpose is to verify that the Primary CCPCH code domain power remains within its specified tolerances. ~~under normal and extreme conditions.~~

6.4.5.4 Method of test

6.4.5.4.1 Initial conditions

6.4.5.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.5.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test. The BS tester must have the ability to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C.

(2) Set the parameters of the BS transmitted signal according to table 6.9.

Table 6.9: Parameters of the BS transmitted signal for Primary CCPCH power testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slots carrying PCCPCH	TS 0 and TS 8
Number of additional DPCH in TS 0 and TS 8	3
BS output power setting	PRAT
Relative power of PCCPCH	¼ of BS output power
Relative power of each DPCH in TS 0 and TS 8	¼ of BS output power
Data content of DPCH	real life (sufficient irregular)

6.4.5.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test. The BS tester must have the ability to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C.

(2) Set the parameters of the BS transmitted signal according to table 6.9A.

Table 6.9A: Parameters of the BS transmitted signal for Primary CCPCH power testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots carrying PCCPCH	TS 0
BS output power setting	PRAT
Relative power of PCCPCH	½ of BS output power
Data content of DPCH	real life (sufficient irregular)

6.4.5.4.2 Procedure

6.4.5.4.2.1 3,84 Mcps TDD option

(1) Measure the PCCPCH code domain power in TS 0 and TS 8 by applying the global in-channel Tx test method described in Annex C.

(2) Reduce the base station output power by 2 dB, 5 dB and 13 dB, without changing the relative powers of the PCCPCH and the DPCHs, and repeat step (1) for each output power setting.

6.4.5.4.2.2 1,28 Mcps TDD option

(1) Measure the PCCPCH code domain power in TS 0 by applying the global in-channel Tx test method described in Annex C.

(2) Reduce the base station output power by 2 dB, 5 dB and 13 dB, without changing the relative powers of the PCCPCH and the DPCHs, and repeat step (1) for each output power setting.

6.4.5.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The Primary CCPCH power, measured according to subclause 6.4.5.4.2, shall be within the limits defined in table 6.10

Table 6.10: Test Requirements for errors between Primary CCPCH power and the broadcast value

Output power in slot, dB	PCCPCH power tolerance
PRAT - 3 < Pout ≤ PRAT + 2	+/- 3,3 dB
PRAT - 6 < Pout ≤ PRAT - 3	+/- 4,3 dB
PRAT - 13 < Pout ≤ PRAT - 6	+/- 5,8 dB

---NEXT SECTION---

6.6.2.2 Adjacent Channel Leakage power Ratio (ACLR)

6.6.2.2.1 Definition and applicability

Adjacent Channel Leakage power Ratio (ACLR) is the ratio of the RRC filtered mean power centered on the assigned channel frequency to the RRC filtered mean power centered on an adjacent channel frequency. The requirements shall apply for all configurations of BS (single carrier or multi-carrier), and for all operating modes foreseen by the manufacturer's specification.

In some cases the requirement is expressed as adjacent channel leakage power, which is the RRC filtered mean power for the given bandwith of the victim system on the adjacent channel frequency.~~the maximum absolute emission level on the adjacent channel frequency measured with a filter that has a Root Raised Cosine (RRC) filter response with roll-off α=0,22 and a bandwidth equal to the chip rate of the victim system.~~

In this subclause, different requirements shall apply to Wide Area BS and Local Area BS.

3GPP TSR RAN WG4 Meeting #24 **R4-021216**

Helsinki, Finland 12 - 16 August 2002

CR-Form-v7

CHANGE REQUEST

⌘ **25.142** **CR** **141** ⌘ **rev** ⌘ Current version: **5.1.0** ⌘

*For **HELP** on using this form, see bottom of this page or look at the pop-up text over the ⌘ symbols.*

Proposed change affects: UICC apps⌘ ☐ ME ☐ Radio Access Network ☒ Core Network ☐

Title:	⌘	Correction of Node B test configurations
Source:	⌘	RAN WG4
Work item code:	⌘	TEI5
Date:	⌘	21/08/2002
Category:	⌘	**F**
Release:	⌘	Rel-5

Use one of the following categories:
F *(correction)*
A *(corresponds to a correction in an earlier release)*
B *(addition of feature),*
C *(functional modification of feature)*
D *(editorial modification)*
Detailed explanations of the above categories can be found in 3GPP TR 21.900.

Use one of the following releases:
2 (GSM Phase 2)
R96 (Release 1996)
R97 (Release 1997)
R98 (Release 1998)
R99 (Release 1999)
Rel-4 (Release 4)
Rel-5 (Release 5)
Rel-6 (Release 6)

Reason for change:	⌘	1- In the current status of TS25.142, some Node B tests are performed with configurations that excludes explicitely physical channels other than DPCH (all power is dedicaded to DPCH). However, P-CCPCH has to be transmitted on TS0 in 1.28 Mcps TDD option according TS25.221 and PCCPCH and SCH need to be transmitted on at least one DL time slot for 3.84 Mcps TDD option. Therefore it might be difficult to configure a Node B according the current test configurations without violating RAN1 requirements.
Summary of change:	⌘	1-TS used for SCH and PCCPCH for 3,84 Mcps TDD option is specified. 2-''Time slots under test'' are specified. This exclude the time slot where PCCPCH and SCH (for the 3,84 Mcps TDD option) are mapped. 3- It is specified in section 5.13 ''Selection of configurations for testing'' that measurements shall be done within the time slots under test.
Consequences if not approved:	⌘	1-Current test configurations may be impossible for Node B strictly following RAN1 specifications.

Clauses affected:	⌘	5.13, 6.2, 6.3, 6.4.2, 6.4.3, 6.4.4, 6.5.2, 6.6.1,6.6.2.1, 6.6.2.2.4, 6.6.3.3, 6.7.3, 6.8.2, 7.7.4

	Y	N		
Other specs ⌘		X	Other core specifications	⌘

affected:	X Test specifications X O&M Specifications	
Other comments: ⌘		

How to create CRs using this form:
Comprehensive information and tips about how to create CRs can be found at http://www.3gpp.org/specs/CR.htm. Below is a brief summary:

1) Fill out the above form. The symbols above marked ⌘ contain pop-up help information about the field that they are closest to.

2) Obtain the latest version for the release of the specification to which the change is proposed. Use the MS Word "revision marks" feature (also known as "track changes") when making the changes. All 3GPP specifications can be downloaded from the 3GPP server under ftp://ftp.3gpp.org/specs/ For the latest version, look for the directory name with the latest date e.g. 2001-03 contains the specifications resulting from the March 2001 TSG meetings.

3) With "track changes" disabled, paste the entire CR form (use CTRL-A to select it) into the specification just in front of the clause containing the first piece of changed text. Delete those parts of the specification which are not relevant to the change request.

5.13 Selection of configurations for testing

Measurements shall be performed within the time slots under test as specified individually for each test within the subclause "Initial conditions".

Most tests in this TS are only performed for a subset of the possible combinations of test conditions. For instance:

- Not all TRXs in the configuration may be specified to be tested.
- Only one RF channel may be specified to be tested.
- Only one timeslot may be specified to be tested.

When a test is performed by a test laboratory, the choice of which combinations are to be tested shall be specified by the laboratory. The laboratory may consult with operators, the manufacturer or other bodies.

When a test is performed by a manufacturer, the choice of which combinations are to be tested may be specified by an operator.

---NEXT SECTION---

6 Transmitter characteristics

6.1 General

Unless otherwise stated, all measurements shall be made at the BS antenna connector.

6.2 Maximum output power

6.2.1 Definition and applicability

Maximum output power (Pmax) and rated output power (PRAT) are defined in subclause 3.1.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.2.2 Minimum Requirements

In normal conditions, the base station maximum output power shall remain within +2 dB and –2 dB of the manufacturer's rated output power.

In extreme conditions, the base station maximum output power shall remain within +2,5 dB and –2,5 dB of the manufacturer's rated output power.

In certain regions, the minimum requirement for normal conditions may apply also for some conditions outside the ranges defined for the Normal test environment in subclause 5.9.1.

The normative reference for this requirement is TS 25.105 [1] subclause 6.2.1.1.

6.2.3 Test purpose

The test purpose is to verify the accuracy of the maximum output power across the frequency range and under normal and extreme conditions for all transmitters in the BS.

6.2.4 Method of test

6.2.4.1 Initial conditions

6.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

In addition, on one UARFCN only, the test shall be performed under extreme power supply as defined in subclause 5.9.4.

NOTE: Tests under extreme power supply also test extreme temperature.

6.2.4.1.1 3,84 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the power measuring equipment to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.1.

Table 6.1: Parameters of the transmitted signal for maximum output power test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.2.4.1.2 1,28 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the power measuring equipment to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.1A.

Table 6.1A: Parameters of the transmitted signal for maximum output power test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.2.4.2 Procedure

6.2.4.2.1 3,84 Mcps TDD option

(1) Measure thermal power of the BS output signal over the 2464 active chips of an even time slot TS i (this excludes the guard periods), and with a measurement bandwidth of at least 5 MHz.

(2) Run step (1) for RF channels Low / Mid / High.

6.2.4.2.2 1,28 Mcps TDD option

(1) Measure thermal power of the BS output signal over the 848 active chips of an even time slot TS i (this excludes the guard periods), and with a measurement bandwidth of at least 1,6 MHz.

(2) Run step (1) for RF channels Low / Mid / High.

6.2.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

In normal conditions, the measured output power, derived according to subclause 6.2.4.2, shall remain within +2,7 dB and –2,7 dB of the manufacturer's rated output power.

In extreme conditions, the measured output power, derived according to subclause 6.2.4.2, shall remain within +3,2 dB and –3,2 dB of the manufacturer's rated output power.

6.3 Frequency stability

6.3.1 Definition and applicability

Frequency stability is the ability of the BS to transmit at the assigned carrier frequency.

In this subclause, different requirements shall apply to Wide Area BS and Local Area BS.

6.3.2 Minimum Requirements

The modulated carrier frequency of the BS is observed over a period of one timeslot. The frequency error shall be within the accuracy range given in Table 6.1B.

Table 6.1B: Frequency error Minimum Requirements

BS class	Accuracy
Wide Area BS	±0,05 ppm
Local Area BS	±0,1 ppm

The normative reference for this requirement is TS 25.105 [1] subclause 6.3.1.1 for the 3,84 Mcps TDD option and subclause 6.3.1.2 for the 1,28 Mcps TDD option.

TS 25.105 subclause 6.3 specifies the additional requirement that the BS shall use the same frequency source for both RF generation and the chip clock. Compliance with this requirement is demonstrated by manufacturer's declaration; see subclause 5.4; a dedicated conformance test for this requirement is not defined.

6.3.3 Test purpose

The test purpose is to verify the accuracy of the carrier frequency across the frequency range and under normal and extreme conditions.

6.3.4 Method of test

6.3.4.1 Initial conditions

6.3.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

The following additional test shall be performed:

On each of B, M and T, the test shall be performed under extreme power supply as defined in subclause 5.9.4.

NOTE: Tests under extreme power supply also test extreme temperature.

6.3.4.1.1 3,84 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the tester to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.2.

Table 6.2: Parameters of the transmitted signal for frequency stability test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
Number of DPCH in each time slot under test~~active TS~~	1
BS output power setting	PRAT
Data content of DPCH	real life (sufficient irregular)

6.3.4.1.2 1,28 Mcps TDD option

(1) The transmitter under test and all other transmitters of the base station (if any) are switched on.

(2) The power of the transmitters not under test (if any) are controlled down.

(3) Connect the tester to the BS antenna connector.

(4) Set the parameters of the transmitted signal according to table 6.2A.

Table 6.2A: Parameters of the transmitted signal for Frequency stability test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0, 4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
Number of DPCH in each time slot under test~~active TS~~	1
BS output power setting	PRAT
Data content of DPCH	real life (sufficient irregular)

6.3.4.2 Procedure

(1) Measure the frequency error delta f across one burst (time slot), by applying the global in-channel Tx test method described in Annex C.

(2) Repeat step (1) for 200 bursts (time slots).

(3) Run steps (1) and (2) for RF channels Low / Mid / High.

6.3.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

For all measured bursts (time slots), the frequency error, derived according to subclause 6.3.4.2, shall be within the accuracy range given in table 6.2B.

Table 6.2B: Frequency error Test Requirements

BS class	Accuracy
Wide Area BS	± (0,05 ppm + 12 Hz)
Local Area BS	± (0,1 ppm + 12 Hz)

6.4 Output power dynamics

6.4.1 Inner loop power control

Inner loop power control is the ability of the BS transmitter to adjust its code domain power in response to the UL received signal.

For inner loop correction on the Downlink Channel, the base station adjusts the code domain power of a power controlled CCTrCH in response to each valid power control bit received from the UE on the Uplink Traffic Channel based on the mapping of the TPC bits in uplink CCTrCH to downlink CCTrCH. Inner loop control is based on SIR measurements at the UE receiver, and the corresponding TPC commands are generated by the UE.

6.4.2 Power control steps

6.4.2.1 Definition and applicability

The power control step is the step change in the DL code domain power in response to a TPC message from the UE.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.2.2 Minimum Requirements

The power control step sizes in the DL shall be 1 dB, 2 dB and 3 dB.

The tolerance of the code domain power and the greatest average rate of change in code domain power due to the power control step shall be within the range shown in Table 6.3.

Table 6.3: Power control step size tolerance

Step size	Tolerance	Range of average rate of change in code domain power per 10 steps	
		Minimum	maximum
1dB	± 0,5 dB	± 8 dB	± 12 dB
2dB	± 0,75 dB	± 16 dB	± 24 dB
3dB	± 1 dB	± 24 dB	± 36 dB

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.2.1.

6.4.2.3 Test purpose

The DL power control is applied to adjust the BS code domain power to a value that is sufficiently high to generate a SIR at the UE receiver equal to the target SIR, while limiting the intercell interference.

The test purpose is to verify the ability of the BS to interpret received TPC commands in a correct way and to adjust its code domain power according to these commands with the specified accuracy.

6.4.2.4 Method of test

6.4.2.4.1 Initial conditions

6.4.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.2.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Disable closed loop power control in the BS under test.

(3) Set the initial parameters of the BS transmitted signal according to table 6.4.

(4) Operate the BS in such a mode that it is able to interpret received TPC commands.

(5) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.4: Initial parameters of the BS transmitted signal for power control steps test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
Number of DPCH in each time slot under test~~active TS~~	1
DPCH power	Minimum
Data content of DPCH	real life (sufficient irregular)

6.4.2.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Disable closed loop power control in the BS under test.

(3) Set the initial parameters of the BS transmitted signal according to table 6.4A.

(4) Operate the BS in such a mode that it is able to interpret received TPC commands.

(5) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.4A: Initial parameters of the BS transmitted signal for power control steps test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0, 4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
Number of DPCH in each time slot under test~~active TS~~	1
DPCH power	Minimun
Data content of DPCH	real life (sufficient irregular)

6.4.2.4.2 Procedure

6.4.2.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH. This sequence shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS) and shall consist of a series of TPC commands with content "Increase Tx power", followed by a series of TPC commands with content "Decrease Tx power". Each of these series should be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum and its minimum, respectively.

(3) Measure the code domain power of the active DPCH over the 2464 active chips of each even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Based on the measurement made in step (3), calculate the power control step sizes and the average rate of change per 10 steps.

(5) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (4).

6.4.2.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH. This sequence shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS) and shall consist of a series of TPC commands with content "Increase Tx power", followed by a series of TPC commands with content "Decrease Tx power". Each of these series should be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum and its minimum, respectively.

(3) Measure the code domain power of the active DPCH over the 848 active chips of each even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Based on the measurement made in step (3), calculate the power control step sizes and the average rate of change per 10 steps.

(5) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (4).

6.4.2.5 Test Requirements

NOTE: If the Test Requirements below differ from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.4.2.5.1 3,84 Mcps TDD option

For all measurements, the tolerance of the power control step sizes and the average rate of change per 10 steps shall be within the limits given in Table 6.5.

Table 6.5: Test Requirements for power control step size tolerance

Step size	Single step tolerance	Range of average rate of change in code domain power per 10 steps	
		Minimum	maximum
1dB	± 0,6 dB	± 7,7 dB	± 12,3 dB
2dB	± 0,85 dB	± 15,7 dB	± 24,3 dB
3dB	± 1,1 dB	± 23,7 dB	± 36,3 dB

In case, the power control step size is set to 3 dB, the number of power control steps feasible within the power control dynamic range of the BS under test may be less than 10. In this case, the evaluation of the average rate of change in

code domain power shall be based on the number of power control steps actually feasible, and the permitted range of average rate of change shall be reduced compared to the values given in table 6.5 in proportion to the ratio (number of power control steps actually feasible /10).

EXAMPLE: If the number of power control steps actually feasible is 9, the minimum and maximum value of the range of average rate of change in code domain power are given by ±21,3 dB and ±32,7 dB, respectively.

6.4.2.5.2 1,28 Mcps TDD option

For all measurements, the tolerance of the power control step sizes and the average rate of change per 10 steps shall be within the limits given in Table 6.5.

In case, the power control step size is set to 3 dB, the number of power control steps feasible within the power control dynamic range of the BS under test may be less than 10. In this case, the evaluation of the average rate of change in code domain power shall be based on the number of power control steps actually feasible, and the permitted range of average rate of change shall be reduced compared to the values given in table 6.5 in proportion to the ratio (number of power control steps actually feasible /10).

EXAMPLE: If the number of power control steps actually feasible is 9, the minimum and maximum value of the range of average rate of change in code domain power are given by 21,6 dB and 32,4 dB, respectively.

6.4.3 Power control dynamic range

6.4.3.1 Definition and applicability

The power control dynamic range is the difference between the maximum and the minimum code domain power of one power controlled code channel for a specified reference condition.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.3.2 Minimum Requirements

The DL power control dynamic range shall be greater than or equal to 30 dB.

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.3.1.

6.4.3.3 Test purpose

The test purpose is to verify the ability of the BS to control the code domain power of a single code signal over the specified dynamic range.

6.4.3.4 Method of test

6.4.3.4.1 Initial conditions

6.4.3.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.3.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.6.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;

- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.6: Parameters of the BS transmitted signal for power control dynamic range test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
Number of DPCH in each time slot under test~~active TS~~	1
Data content of DPCH	real life (sufficient irregular)

6.4.3.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.6A.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyze the output signal of the BS under test with respect to code domain power, by applying the global in-channel Tx test method described in Annex C;

- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.6A: Parameters of the BS transmitted signal for power control dynamic range test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0, 4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
Number of DPCH in each time slot under test~~active TS~~	1
Data content of DPCH	real life (sufficient irregular)

6.4.3.4.2 Procedure

6.4.3.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Increase Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(3) Measure the code domain power of the active DPCH over the 2464 active chips of an even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(5) Measure the code domain power of the active DPCH over the 2464 active chips of an even time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(6) Determine the power control dynamic range by calculating the difference between the maximum code domain power measured in step (3) and the minimum code domain power measured in step (5).

(7) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (6).

6.4.3.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Increase Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its maximum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(3) Measure the code domain power of the active DPCH over the 848 active chips of an receive time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(4) Set the BS tester to produce a sequence of TPC commands related to the active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the code domain power of the active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(5) Measure the code domain power of the active DPCH over the 848 active chips of a receive time slot TS i (this excludes the guard period) by applying the global in-channel Tx test method described in Annex C.

(6) Determine the power control dynamic range by calculating the difference between the maximum code domain power measured in step (3) and the minimum code domain power measured in step (5).

(7) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) to (6).

6.4.3.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The power control dynamic range derived according to subclause 6.4.3.4.2 shall be greater than or equal to 29,7 dB

6.4.4 Minimum output power

6.4.4.1 Definition and applicability

The minimum controlled output power of the BS is when the power is set to a minimum value.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.4.4.2 Minimum Requirements

The DL minimum output power shall be less than or equal to:

Maximum output power - 30 dB.

The normative reference for this requirement is TS 25.105 [1] subclause 6.4.4.1.

6.4.4.3 Test purpose

The test purpose is to verify the ability of the BS to reduce its output power to a specified value.

6.4.4.4 Method of test

6.4.4.4.1 Initial conditions

6.4.4.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.4.4.4.1.1 3,84 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.7.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability:

- to analyse the output signal of the BS under test with respect to thermal power;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.7: Parameters of the BS transmitted signal for minimum power test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
Number of DPCH in each time slot under test~~active TS~~	1
Data content of DPCH	real life (sufficient irregular)

6.4.4.4.1.2 1,28 Mcps TDD option

(1) Connect the BS tester to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.7A.

(3) Operate the BS in such a mode that it is able to interpret received TPC commands

(4) Start BS transmission.

NOTE: The BS tester used for this test must have the ability

- to analyse the output signal of the BS under test with respect to thermal power;
- to simulate an UE with respect to the generation of TPC commands embedded in a valid UE signal.

Table 6.7A: Parameters of the BS transmitted signal for minimum power test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.4.4.4.2 Procedure

6.4.4.4.2.1 3,84 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to all active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the output power of all active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the odd time slots TS i (receive time slots of the BS).

(3) Measure the power of the BS output signal over the 2464 active chips of an even and non zero time slot TS i (this excludes the guard period), and with a measurement filter that has a RRC filter response with a roll off $\alpha = 0,22$ and a bandwidth equal to the chip rate. The power is determined by calculating the RMS value of the signal samples at the measurement filter output taken at the decision points.

(4) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) and (3).

6.4.4.4.2.2 1,28 Mcps TDD option

(1) Configure the BS transmitter to enable power control steps of size 1 dB.

(2) Set the BS tester to produce a sequence of TPC commands related to all active DPCH, with content "Decrease Tx power". This sequence shall be sufficiently long so that the output power of all active DPCH is controlled to reach its minimum, and shall be transmitted to the BS within the receive time slots TS i of the BS.

(3) Measure the power of the BS output signal over the 848 active chips of a receive time slot TS i (this excludes the guard period), and with a measurement filter that has a RRC filter response with a roll off $\alpha = 0,22$ and a bandwidth equal to the chip rate. The power is determined by calculating the RMS value of the signal samples at the measurement filter output taken at the decision points.

(4) Configure the BS transmitter to enable power control steps of 2 dB and of 3 dB, respectively, and repeat steps (2) and (3).

6.4.4.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

For all measurements, the minimum output power derived in step (4) of subclause 6.4.4.4.2 shall be at least 29,3 dB below the maximum output power as declared by the manufacturer; see 6.2.

---NEXT SECTION---

6.5 Transmit ON/OFF power

6.5.1 Transmit OFF power

6.5.1.1 Definition and applicability

The transmit OFF power is defined as the RRC filtered mean power measured over one chip when the transmitter is off. The transmit OFF power state is when the BS does not transmit.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.5.1.2 Minimum Requirements

6.5.1.2.1 3,84 Mcps TDD option

The transmit OFF power shall be less than –79 dBm.

6.5.1.2.2 1,28 Mcps TDD option

The transmit OFF power shall be less than –82 dBm.

The normative reference for this requirement is TS 25.105 [1] subclause 6.5.1.

6.5.1.3 Test purpose

This test verifies the ability of the BS to reduce its transmit OFF power to a value below the specified limit. This ability is needed to minimize the interference for other users receiving on the same frequency.

6.5.1.4 Method of test

6.5.1.4.1 Initial conditions

The conformance testing of transmit OFF power is included in the conformance testing of transmit ON/OFF time mask; therefore, see subclause 6.5.2.4.1 for initial conditions.

6.5.1.4.2 Procedure

The conformance testing of transmit OFF power is included in the conformance testing of transmit ON/OFF time mask; therefore, see subclause 6.5.2.4.2 for procedure.

6.5.1.5 Test Requirements

The conformance testing of transmit OFF power is included in the conformance testing of transmit ON/OFF time mask; therefore, see subclause 6.5.2.5 for test requirements.

6.5.2 Transmit ON/OFF time mask

6.5.2.1 Definition and applicability

The transmit ON/OFF time mask defines the ramping time allowed for the BS between transmit OFF power and transmit ON power.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.5.2.2 Minimum Requirements

6.5.2.2.1 3,84 Mcps TDD option

The transmit power level versus time should meet the mask specified in figure 6.1.

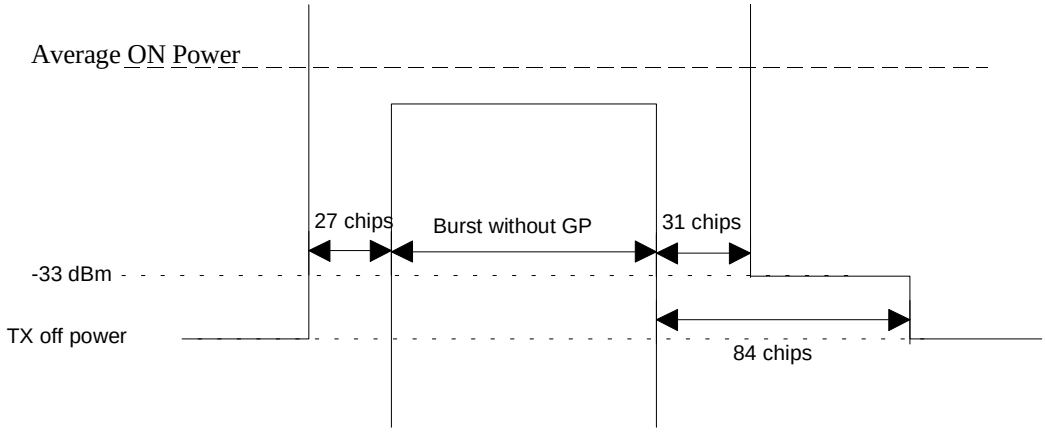

Figure 6.1: Transmit ON/OFF template

6.5.2.2.2 1,28 Mcps TDD option

The transmit power level versus time should meet the mask specified in figure 6.1A.

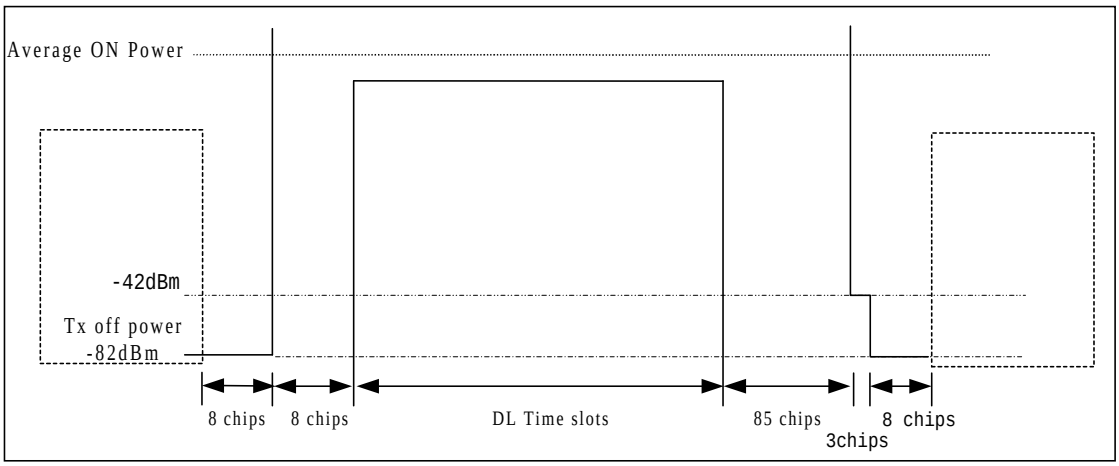

Figure 6.1A: Transmit ON/OFF template for 1,28 Mcps TDD option

The normative reference for this requirement is TS 25.105 [1] subclause 6.5.2.

6.5.2.3 Test purpose

This test verifies the ability of the BS to reduce its transmit power outside of the active part of the Tx time slot (burst without guard period) to values below specified limits. This ability is needed to minimize the interference for other users receiving on the same frequency.

6.5.2.4 Method of test

6.5.2.4.1 Initial conditions

6.5.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.5.2.4.1.1 3,84 Mcps TDD option

(1) Connect the power measuring equipment to the BS antenna connector.

(2) Set the parameters of the transmitted signal according to table 6.11.

Table 6.11: Parameters of the transmitted signal for transmit ON/OFF time mask test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	Real life (sufficient irregular)

6.5.2.4.1.2 1,28 Mcps TDD option

(1) Connect the power measuring equipment to the BS antenna connector.

(2) Set the parameters of the transmitted signal according to table 6.11A.

Table 6.11A: Parameters of the transmitted signal for transmit ON/OFF time mask test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is UpPCH,1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.5.2.4.2 Procedure

6.5.2.4.2.1 3,84 Mcps TDD option

(1) Measure the RRC filtered mean power of the BS output signal chipwise (i.e. averaged over time intervals of one chip duration) over the period starting 65 chips before the start of the odd time slots TS i (receive time slots of the BS), and ending 27 chips before the next even time slot (transmit time slot of the BS) starts.

6.5.2.4.2.2 1,28 Mcps TDD option

(1) Measure the RRC filtered mean power of the BS output signal chipwise (i.e. averaged over time intervals of one chip duration) over the transmit off power period starting 11 chips before the start of the receive time slot TS i = UpPCH, and ending 8 chips before the next transmit time slot TS i=4 starts.

6.5.2.5 Test Requirements

NOTE: If the Test Requirements below differ from the Minimum Requirements, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.5.2.5.1 3,84 Mcps TDD option

Each value of the power measured according to subclause 6.5.2.4.2.1 shall be below – 32,3 dBm in the period from 32 chips to 84 chips after the burst and below – 77 dBm in the period where the Tx OFF power specification is applicable.

6.5.2.5.2 1,28 Mcps TDD option

Each value of the power measured according to subclause 6.5.2.4.2.2 shall be below – 41,3 dBm in the period from 85 chips to 88 chips after the burst and below – 80 dBm in the period where the Tx OFF power specification is applicable.

6.6 Output RF spectrum emissions

6.6.1 Occupied bandwidth

6.6.1.1 Definition and applicability

Occupied bandwidth is a measure of the bandwidth containing 99% of the total integrated power for transmitted spectrum and is centered on the assigned channel frequency.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.6.1.2 Minimum Requirements

6.6.1.2.1 3,84 Mcps TDD option

The occupied bandwidth shall be less than 5 MHz based on a chip rate of 3,84 Mcps.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.1.1.

6.6.1.2.2 1,28 Mcps TDD option

The occupied bandwidth shall be less than 1,6 MHz based on a chip rate of 1,28 Mcps.

The reference for this requirement is TS 25.105 [1] subclause 6.6.1.2.

6.6.1.3 Test purpose

The occupied bandwidth, defined in the Radio Regulations of the International Telecommunication Union ITU, is a useful concept for specifying the spectral properties of a given emission in the simplest possible manner; see also Recommendation ITU-R SM.328-9 [7]. The test purpose is to verify that the emission of the BS does not occupy an excessive bandwidth for the service to be provided and is, therefore, not likely to create interference to other users of the spectrum beyond undue limits.

6.6.1.4 Method of test

6.6.1.4.1 Initial conditions

6.6.1.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.6.1.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.12.

Table 6.12: Parameters of the BS transmitted signal for occupied bandwidth testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each each time slot under testactive TS	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	Real life (sufficient irregular)

6.6.1.4.1.2 1,28 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.12A.

Table 6.12A: Parameters of the BS transmitted signal for occupied bandwidth testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under testactive TS	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.1.4.2 Procedure

6.6.1.4.2.1 3,84 Mcps TDD option

(1) Measure the power of the transmitted signal with a measurement filter of bandwidth 30 kHz. The characteristic of the filter shall be approximately Gaussian (typical spectrum analyzer filter). The centre frequency of the filter shall be stepped in contiguous 30 kHz steps from a minimum frequency, which shall be (7,5 – 0,015) MHz below the assigned channel frequency of the transmitted signal, up to a maximum frequency, which shall be (7,5 – 0,015) MHz above the assigned channel frequency of the transmitted signal. The time duration of each step shall be sufficiently long to capture one active time slot. The measured power shall be recorded for each step.

(2) Determine the total output power by accumulating the recorded power measurement results of all steps.

(3) Sum up the recorded power measurement results, starting from the step at the minimum frequency defined in (1) up to the step at a lower limit frequency by which this sum is equal to or greater than 0.5 % of the total output power determined in (2). This limit frequency is recorded as "Lower Frequency".

(4) Sum up the recorded power measurement results, starting from the step at the maximum frequency defined in (1) down to the step at an upper limit frequency by which this sum is equal to or greater than 0.5 % of the total output power determined in (2). This limit frequency is recorded as "Upper Frequency".

(5) Calculate the occupied bandwidth as the difference between the "Upper Frequency" obtained in (3) and the "Lower Frequency" obtained in (4).

6.6.1.4.2.2 1,28 Mcps TDD option

(1) Measure the power of the transmitted signal with a measurement filter of bandwidth 30 kHz. The characteristic of the filter shall be approximately Gaussian (typical spectrum analyser filter). The centre frequency of the filter shall be stepped in contiguous 30 kHz steps from a minimum frequency, which shall be (2,4 – 0,015) MHz below the assigned channel frequency of the transmitted signal, up to a maximum frequency, which shall be (2,4 – 0,015) MHz above the assigned channel frequency of the transmitted signal. The time duration of each step shall be sufficiently long to capture one active time slot. The measured power shall be recorded for each step.

(2) Determine the total output power by accumulating the recorded power measurement results of all steps.

(3) Sum up the recorded power measurement results, starting from the step at the minimum frequency defined in (1) up to the step at a lower limit frequency by which this sum is equal to or greater than 0,5 % of the total output power determined in (2). This limit frequency is recorded as "Lower Frequency".

(4) Sum up the recorded power measurement results, starting from the step at the maximum frequency defined in (1) down to the step at an upper limit frequency by which this sum is equal to or greater than 0,5 % of the total output power determined in (2). This limit frequency is recorded as "Upper Frequency".

(5) Calculate the occupied bandwidth as the difference between the "Upper Frequency" obtained in (3) and the "Lower Frequency" obtained in (4).

6.6.1.5 Test Requirements

NOTE: If the Test Requirement below differ from the Minimum Requirements, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.6.1.5.1 3,84 Mcps TDD option

The occupied bandwidth calculated in step (5) of subclause 6.6.1.4.2.1 shall be less than 5 MHz.

6.6.1.5.2 1,28 Mcps TDD option

The occupied bandwidth calculated in step (5) of subclause 6.6.1.4.2.2 shall be less than 1,6 MHz.

6.6.2 Out of band emission

Out of band emissions are unwanted emissions immediately outside the channel bandwidth resulting from the modulation process and non-linearity in the transmitter but excluding spurious emissions. This out of band emission requirement is specified both in terms of a spectrum emission mask and adjacent channel power ratio for the transmitter.

6.6.2.1 Spectrum emission mask

6.6.2.1.1 Definition and applicability

6.6.2.1.1.1 3,84 Mcps TDD option

The spectrum emission mask specifies the limit of the transmitter out of band emissions at frequency offsets from the assigned channel frequency of the wanted signal between 2,5 MHz and 12,5 MHz.

The mask defined in subclause 6.6.2.1.2.1 below may be mandatory in certain regions. In other regions this mask may not be applied.

For regions in which the mask is mandatory, the requirements shall apply to both Wide Area BS and Local Area BS.

6.6.2.1.1.2 1,28 Mcps TDD option

The spectrum emission mask specifies the limit of the transmitter out of band emissions at frequency offsets from the assigned channel frequency of the wanted signal between 0,8 MHz and 4 MHz.

The mask defined in subclause 6.6.2.1.2.2 below may be mandatory in certain regions. In other regions this mask may not be applied.

For regions in which the mask is mandatory, the requirements shall apply to both Wide Area BS and Local Area BS.

6.6.2.1.2 Minimum Requirements

6.6.2.1.2.1 3,84 Mcps TDD option

For regions where this subclause applies, the requirement shall be met by a base station transmitting on a single RF carrier configured in accordance with the manufacturer's specification. Emissions shall not exceed the maximum level specified in tables 6.13 to 6.16 in the frequency range of f_offset from 2,515 MHz to f_offset_{max} from the carrier frequency, where:

- f_offset is the separation between the carrier frequency and the centre of the measurement filter
- f_offset_{max} is either 12,5 MHz or the offset to the UMTS Tx band edge as defined in subclause 4.2, whichever is the greater.

Table 6.13: Spectrum emission mask values, BS maximum output power P ≥ 43 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-14 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-14dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-26 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-13 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	-13 dBm	1 MHz

Table 6.14: Spectrum emission mask values, BS maximum output power 39 ≤ P < 43 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-14 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-14dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-26 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-13 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	P – 56 dB	1 MHz

Table 6.15: Spectrum emission mask values, BS maximum output power 31 ≤ P < 39 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	P – 53 dB	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$P - 53dB - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	P – 65 dB	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	P – 52 dB	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	P – 56 dB	1 MHz

Table 6.16: Spectrum emission mask values, BS maximum output power P < 31 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-22 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-22dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-34 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-21 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	-25 dBm	1 MHz

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.1.1

6.6.2.1.2.2 1,28 Mcps TDD option

For regions where this subclause applies, the requirement shall be met by a base station transmitting on a single RF carrier configured in accordance with the manufacturer's specification. Emissions shall not exceed the maximum level specified in tables 6.13A to 16A in the frequency range of f_offset from 0.815 MHz to f_offset_{max} from the carrier frequency, where:

- f_offset is the separation between the carrier frequency and the centre of the measurement filter
- f_offset_{max} is either 4 MHz or the offset to the UMTS Tx band edge as defined in subclause 4.2, whichever is the greater.

Table 6.13A: Spectrum emission mask values, BS maximum output power P ≥ 34 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	-20 dBm	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$-20dBm - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	-28 dBm	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	-13 dBm	1 MHz

Table 6.14A: Spectrum emission mask values, BS maximum output power 26 ≤ P < 34 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	P-54 dB	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$P - 54dB - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	P-62 dB	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	P - 47 dB	1 MHz

Table 6.16A: Spectrum emission mask values, BS maximum output power P < 26 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	-28 dBm	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$-28dBm - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	-36 dBm	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	-21 dBm	1 MHz

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.1.2.

6.6.2.1.3 Test purpose

The test purpose is to verify that the BS out of band emissions do not result in undue interference to any other system (wideband, narrowband) operating at frequencies close to the assigned channel bandwidth of the wanted signal.

This test is independent of the characteristics of possible victim systems and, therefore, complements the tests on occupied bandwidth in 6.6.1 (verifying the spectral concentration of the BS Tx emissions) and on ACLR in 6.6.2.2 (simulating the perception of other UTRA receivers).

6.6.2.1.4 Method of test

6.6.2.1.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the spectrum emission mask requirements shall be tested with the general test set up specified in section 6.6.2.1.4.1.2 and also with the special test set up for 16QAM capable BS specified in section 6.6.2.1.4.1.3.

6.6.2.1.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.6.2.1.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.17.

Table 6.17: Parameters of the BS transmitted signal for spectrum emission mask testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.2.1.4.1.2 1,28 Mcps TDD option – General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.17A.

Table 6.17A: Parameters of the BS transmitted signal for spectrum emission mask testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.2.1.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.17B.

Table 6.17B: Parameters of the BS transmitted signal for spectrum emission mask testing for 1,28 Mcps TDD - 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each time slot under test~~active TS~~	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-PDSCH	real life (sufficient irregular)
Spreading factor	16

6.6.2.1.4.2 Procedure

6.6.2.1.4.2.1 3,84 Mcps TDD option

Measure the power of the BS spectrum emissions by applying measurement filters with bandwidths as specified in the relevant table in subclause 6.6.2.1.2.1. The characteristic of the filters shall be approximately Gaussian (typical spectrum analyzer filters). The centre frequency of the filter shall be stepped in contiguous steps over the ranges of frequency offsets f_offset as given in the tables. The step width shall be equal to the respective measurement bandwidth. The time duration of each step shall be sufficiently long to capture one active time slot.

For frequency offsets of the measurement filter centre frequency in the range 4,0 MHz ≤ f_offset < f_offset_{max}, the measurement shall be performed by applying filters with measurement bandwidth of 50 kHz or less and integrating the measured results over the nominal measurement bandwidth 1 MHz specified in the tables in subclause 6.6.2.1.2.1.

6.6.2.1.4.2.2 1,28 Mcps TDD option

Measure the power of the BS spectrum emissions by applying measurement filters with bandwidths as specified in the relevant table in subclause 6.6.2.1.2.2. The characteristic of the filters shall be approximately Gaussian (typical spectrum analyzer filters). The centre frequency of the filter shall be stepped in contiguous steps over the ranges of frequency offsets f_offset as given in the tables. The step width shall be equal to the respective measurement bandwidth. The time duration of each step shall be sufficiently long to capture one active time slot.

The measurement shall be performed by applying filters with measurement bandwidth of 50 kHz or less and integrating the measured results over the nominal measurement bandwidth 1 MHz specified in the tables in subclause 6.6.2.1.2.2 when the measurement bandwidth is 1MHz.

6.6.2.1.4.2.3 1,28 Mcps TDD option – 16QAM capable BS

The same procedure specified in 6.6.2.1.4.2.2 applies to 1,28 Mcps TDD option BS supporting 16QAM.

6.6.2.1.5 Test Requirements

NOTE: If the Test Requirements below differ from the Minimum Requirements, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.6.2.1.5.1 3,84 Mcps TDD option

The spectrum emissions measured according to subclause 6.6.2.1.4.2.1 shall not exceed the maximum level specified in tables 6.18 to 6.21 for the appropriate BS maximum output power

Table 6.18: Test Requirements for spectrum emission mask values, BS maximum output power P ≥ 43 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-12,5 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-12{,}5dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-24,5 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-11,5 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	-11,5 dBm	1 MHz

Table 6.19: Test Requirements for spectrum emission mask values, BS maximum output power 39 ≤ P < 43 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-12,5 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-12{,}5dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-24,5 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-11,5 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	P – 54,5 dB	1 MHz

Table 6.20: Test Requirements for spectrum emission mask values, BS maximum output power 31 ≤ P < 39 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	P – 51,5 dB	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$P - 51{,}5dB - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	P – 63,5 dB	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	P – 50,5 dB	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	P – 54,5 dB	1 MHz

Table 6.21: Test Requirements for spectrum emission mask values, BS maximum output power P < 31 dBm

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
2,515 MHz ≤ f_offset < 2,715 MHz	-20,5 dBm	30 kHz
2,715 MHz ≤ f_offset < 3,515 MHz	$-20{,}5dBm - 15 \cdot \left(\frac{f\_offset}{MHz} - 2{,}715 \right) dB$	30 kHz
3,515 MHz ≤ f_offset < 4,0 MHz	-32,5 dBm	30 kHz
4,0 MHz ≤ f_offset < 8,0 MHz	-19,5 dBm	1 MHz
8,0 MHz ≤ f_offset < f_offset_{max}	-23,5 dBm	1 MHz

6.6.2.1.5.2 1,28 Mcps TDD option

The spectrum emissions measured according to subclause 6.6.2.1.4.2.2 shall be within the mask defined in the table 6.18A to 6.21A.

Table 6.18A: Test requirements for spectrum emission mask values, BS maximum output power P ≥ 34 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	-18.5 dBm	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$-18.5dBm - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	-26.5 dBm	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	-11.5 dBm	1 MHz

Table 6.19A: Test requirements for spectrum emission mask values, BS maximum output power 26 ≤ P < 34 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	P-52.5 dB	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$P - 52.5dB - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	P-60.5 dB	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	P – 45.5 dB	1 MHz

Table 6.21A: Test requirements for spectrum emission mask values, BS maximum output power P < 26 dBm for 1,28 Mcps TDD

Frequency offset of measurement filter centre frequency, f_offset	Maximum level	Measurement bandwidth
0.815MHz ≤ f_offset < 1.015MHz	-26.5 dBm	30 kHz
1.015MHz ≤ f_offset < 1.815MHz	$-26.5dBm - 10 \cdot \left(\frac{f\_offset}{MHz} - 1{,}015 \right) dB$	30 kHz
1.815MHz ≤ f_offset < 2.3MHz	-34.5 dBm	30 kHz
2.3MHz ≤ f_offset < f_offset_{max}	-19.5 dBm	1 MHz

6.6.2.1.5.3 1,28 Mcps TDD option – 16QAM capable BS

The spectrum emissions measured according to subclause 6.6.2.1.4.2.3 shall be within the mask defined in the table 6.18A to 6.21A in section 6.6.2.1.5.2.

6.6.2.2 Adjacent Channel Leakage power Ratio (ACLR)

6.6.2.2.1 Definition and applicability

Adjacent Channel Leakage power Ratio (ACLR) is the ratio of the RRC filtered mean power centered on the assigned channel frequency to the RRC filtered mean power centered on an adjacent channel frequency. The requirements shall apply for all configurations of BS (single carrier or multi-carrier), and for all operating modes foreseen by the manufacturer's specification.

In some cases the requirement is expressed as adjacent channel leakage power, which is the maximum absolute emission level on the adjacent channel frequency measured with a filter that has a Root Raised Cosine (RRC) filter response with roll-off α=0,22 and a bandwidth equal to the chip rate of the victim system.

In this subclause, different requirements shall apply to Wide Area BS and Local Area BS.

6.6.2.2.2 Minimum Requirements

6.6.2.2.2.1 Minimum requirement

6.6.2.2.2.1.1 3,84 Mcps TDD option

The ACLR of a single carrier BS or a multi-carrier BS with contiguous carrier frequencies shall be equal to or greater than the limits given in table 6.22.

Table 6.22: BS ACLR limits

BS adjacent channel offset below the first or above the last carrier frequency used	ACLR limit
5 MHz	45 dB
10 MHz	55 dB

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied individually to the single carriers or group of single carriers.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.1.1.

6.6.2.2.2.1.2 1,28 Mcps TDD option

The ACLR of a single carrier BS or a multi-carrier BS with contiguous carrier frequencies shall be equal to or greater than the limits given in Table 6.22A.

Table 6.22A: BS ACLR limits for 1,28 Mcps TDD

BS adjacent channel offset below the first or above the last carrier frequency used	ACLR limit
1,6 MHz	40 dB
3,2 MHz	45 dB

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied individually to the single carriers or group of single carriers.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.1.2

6.6.2.2.2 Additional requirement for operation in the same geographic area with FDD or unsynchronised TDD on adjacent channels

6.6.2.2.2.1 3,84 Mcps TDD option

6.6.2.2.2.1.1 Additional requirement for operation in the same geographic area with unsynchronised TDD on adjacent channels

In case the equipment is operated in the same geographic area with an unsynchronised TDD BS operating on the first or second adjacent frequency, the adjacent channel leakage power of a single carrier BS or a multi-carrier BS with contiguous carrier frequencies shall not exceed the limits specified in table 6.23.

Table 6.23: Adjacent channel leakage power limits for operation in the same geographic area with unsynchronised TDD on adjacent channels

BS Class	BS adjacent channel offset below the first or above the last carrier frequency used	Maximum Level	Measurement Bandwidth
Wide Area BS	5 MHz	-29 dBm	3,84 MHz
Wide Area BS	10 MHz	-29 dBm	3,84 MHz
Local Area BS	5 MHz	-16 dBm	3,84 MHz
Local Area BS	10 MHz	-26 dBm	3,84 MHz

NOTE: The requirements in table 6.23 for the Wide Area BS are based on a coupling loss of 74 dB between the unsynchronised TDD base stations. The requirement in table 6.23 for the Local Area BS ACLR1 (± 5 MHz channel offset) is based on a coupling loss of 87 dB between unsynchronised Wide Area and Local Area TDD base stations. The requirement in table 6.23 for the Local Area BS ACLR2 (± 10 MHz channel offset) is based on a coupling loss of 77 dB between unsynchronised Wide Area and Local Area TDD base stations. The scenarios leading to these requirements are addressed in TR25.942 [9].

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied to those adjacent channels of the single carriers or group of single channels which are used by the TDD BS in the same geographic area.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.2.1.1.

NOTE: The necessary dynamic range to very the conformance requirements specified in table 6.23 is at the limits of the capability of state-of-art measuring equipment.

6.6.2.2.2.2.1.2 Additional requirement for operation in the same geographic area with FDD on adjacent channels

In case the equipment is operated in the same geographic area with a FDD BS operating on the first or second adjacent channel, the adjacent channel leakage power shall not exceed the limits specified in table 6.23AA.

Table 6.23AA: Adjacent channel leakage power limits for operation in the same geographic area with FDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 5 MHz	-36 dBm	3,84 MHz
Wide Area BS	± 10 MHz	-36 dBm	3,84 MHz
Local Area BS	± 5 MHz	-23 dBm	3,84 MHz
Local Area BS	± 10 MHz	-33 dBm	3,84 MHz

NOTE: The requirements in table 6.23AA for the Wide Area BS are based on a coupling loss of 74 dB between the FDD and TDD base stations. The requirements in table 6.23AA for the Local Area BS ACLR1 (± 5 MHz channel offset) are based on a relaxed coupling loss of 87 dB between TDD and FDD base stations. The requirement for the Local Area BS ACLR2 (± 10 MHz channel offset) are based on a relaxed coupling loss of 77 dB between TDD and FDD base stations. The scenarios leading to these requirements are addressed in TR 25.942 [9].

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied to those adjacent channels of the single carriers or group of single channels which are used by the FDD BS in the same geographic area.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.2.1.2.

6.6.2.2.2.2 1,28 Mcps TDD option

6.6.2.2.2.2.1 Additional requirement for operation in the same geographic area with unsynchronised TDD on adjacent channels

In case the equipment is operated in the same geographic area with an unsynchronised TDD BS operating on an adjacent channel, the requirement is specified in terms of adjacent channel leakage power. In geographic areas where only UTRA 1,28 Mcps TDD option is deployed, the adjacent channel leakage power limits shall not exceed the limits specified in table 6.23A, otherwise the limits in table 6.23B shall apply.

Table 6.23A: Adjacent channel leakage power limits for operation in the same geographic area with unsynchronised 1,28 Mcps TDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 1,6 MHz	-29 dBm	1,28 MHz
Wide Area BS	± 3,2 MHz	-29 dBm	1,28 MHz
Local Area BS	± 1,6 MHz	-16 dBm	1,28 MHz
Local Area BS	± 3,2 MHz	-16 dBm	1,28 MHz

Table 6.23B: Adjacent channel leakage power limits for operation in the same geographic area with unsynchronised TDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 3,4 MHz	-29 dBm	3,84 MHz
Local Area BS	± 3,4 MHz	-16 dBm	3,84 MHz

NOTE: The requirements in table 6.23A and 6.23B for the Wide Area BS are based on a coupling loss of 74 dB between the unsynchronised TDD base stations. The requirements in table 6.23A and 6.23B for the Local Area BS are based on a coupling loss of 87 dB between unsynchronised Wide Area and Local Area TDD base stations. The scenarios leading to these requirements are addressed in TR25.942 [9].

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.2.2.1.

6.6.2.2.2.2.2 Additional requirement for operation in the same geographic area with FDD on adjacent channels

In case the equipment is operated in the same geographic area with a FDD BS operating on an adjacent channel, the adjacent channel leakage power shall not exceed the limits specified in table 6.23C. This requirement is only applicable if the equipment is intended to operate in frequency bands specified in 4.2 a) and the highest carrier frequency used is in the range 1916,2 – 1920 MHz.

Table 6.23C: Adjacent channel leakage power limits for operation in the same geographic area with FDD on adjacent channels

BS Class	Center Frequency for Measurement	Maximum Level	Measurement Bandwidth
Wide Area BS	1922,6 MHz	-36 dBm	3,84 MHz
Local Area BS	1922,6 MHz	-23 dBm	3,84 MHz

NOTE: The requirement in table 6.23C for Wide Area BS is based on a relaxed coupling loss of 74 dB between the TDD and FDD base stations. The requirement in table 6.23C for Local Area BS is based on a relaxed coupling loss of 87 dB between TDD and FDD base stations. The scenarios leading to these requirements are addressed in TR 25.942 [9].

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.2.2.2.

6.6.2.2.3 Additional requirement in case of co-siting with unsynchronised TDD BS or FDD BS operating on an adjacent channel

6.6.2.2.3.1 3,84 Mcps TDD option

6.6.2.2.3.1.1 Additional requirement in case of co-siting with unsynchronised TDD BS operating on an adjacent channel

In case the equipment is co-sited to an unsynchronised TDD BS operating on the first or second adjacent frequency, the adjacent channel leakage power of a single carrier BS or a multi-carrier BS with contiguous carrier frequencies shall not exceed the limits specified in table 6.24.

Table 6.24: Adjacent channel leakage power limits in case of co-siting with unsynchronised TDD on adjacent channels

BS Class	BS adjacent channel offset below the first or above the last carrier frequency used	Maximum Level	Measurement Bandwidth
Wide Area BS	5 MHz	-73 dBm	3,84 MHz
Wide Area BS	10 MHz	-73 dBm	3,84 MHz
Local Area BS	5 MHz	-31 dBm	3,84 MHz
Local Area BS	10 MHz	-31 dBm	3,84 MHz

NOTE: The requirements in table 6.24 for the Wide Area BS are based on a minimum coupling loss of 30 dB between unsynchronised TDD base stations. The requirements in table 6.24 for the Local Area BS are based on a minimum coupling loss of 45 dB between unsynchronised Local Area base stations. The co-location of different base station classes is not considered.

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied to those adjacent channels of the single carriers or group of single channels which are used by the co-sited TDD BS.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.3.1.1.

NOTE: The necessary dynamic range of the measuring equipment to verify the conformance requirements specified in table 6.24 for the Wide Area BS is dependent on the BS output power. If the BS output power is larger than –10 dBm, the necessary dynamic range is beyond the capability of state-of-the-art measuring equipment; direct verification of the conformance requirements is not feasible. Alternatively, indirect measurement methods need to be defined.

6.6.2.2.2.3.1.2 Additional requirement in case of co-siting with FDD BS operating on adjacent channels

In case the equipment is co-sited to a FDD BS operating on the first or second adjacent channel, the adjacent channel leakage power shall not exceed the limits specified in table 6.24A.

Table 6.24A: Adjacent channel leakage power limits in case of co-siting with FDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 5 MHz	-80 dBm	3,84 MHz
Wide Area BS	± 10 MHz	-80 dBm	3,84 MHz

NOTE: The requirements in table 6.24A are based on a minimum coupling loss of 30 dB between base stations. The co-location of different base station classes is not considered. A co-location requirement for the Local Area TDD BS is intended to be part of a later release.

If a BS provides multiple non-contiguous single carriers or multiple non-contiguous groups of contiguous single carriers, the above requirements shall be applied to those adjacent channels of the single carriers or group of single channels which are used by the co-sited FDD BS.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.3.1.2.

6.6.2.2.2.3.2 1,28 Mcps TDD option

6.6.2.2.2.3.2.1 Additional requirement in case of co-siting with unsynchronised TDD BS operating on an adjacent channel

In case the equipment is co-sited to an unsynchronised TDD BS operating on an adjacent channel, the requirement is specified in terms of adjacent channel leakage power. In geographic areas where only UTRA 1,28 Mcps TDD option is deployed, the adjacent channel leakage power shall not exceed the limits specified in table 6.24B, otherwise the limits in table 6.24C shall apply.

Table 6.24B: Adjacent channel leakage power limits in case of co-siting with unsynchronised 1,28 Mcps TDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 1,6 MHz	-73 dBm	1,28 MHz
Wide Area BS	± 3,2 MHz	-73 dBm	1,28 MHz
Local Area BS	± 1,6 MHz	-34 dBm	1,28 MHz
Local Area BS	± 3,2 MHz	-34 dBm	1,28 MHz

Table 6.24C: Adjacent channel leakage power limits in case of co-siting with unsynchronised TDD on an adjacent channel

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 3,4 MHz	-73 dBm	3,84 MHz
Local Area BS	± 3,4 MHz	-31 dBm	3,84 MHz

NOTE: The requirements in table 6.24B and 6.24C for the Wide Area BS are based on a minimum coupling loss of 30 dB between unsynchronised TDD base stations. The requirements in table 6.24B and 6.24C for the Local Area BS are based on a minimum coupling loss of 45 dB between unsynchronised Local Area base stations. The co-location of different base station classes is not considered.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.3.2.1.

6.6.2.2.2.3.2.2 Additional requirement in case of co-siting with FDD BS operating on an adjacent channel

In case the equipment is co-sited to a FDD BS operating on an adjacent channel, the adjacent channel leakage power shall not exceed the limits specified in table 6.24D. This requirement is only applicable if the equipment is intended to operate in frequency bands specified in 4.2 a) and the highest carrier frequency used is in the range 1916,2 – 1920 MHz.

Table 6.24D: Adjacent channel leakage power in case of co-siting with UTRA FDD on an adjacent channel

BS Class	Center Frequency for Measurement	Maximum Level	Measurement Bandwidth
Wide Area BS	1922,6 MHz	-80 dBm	3,84 MHz

NOTE: The requirements in table 6.24D are based on a minimum coupling loss of 30 dB between base stations. The co-location of different base station classes is not considered. A co-location requirement for the Local Area TDD BS is intended to be part of a later release.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.2.2.3.2.2.

6.6.2.2.3 Test purpose

The test purpose is to verify the ability of the BS to limit the interference produced by the transmitted signal to other UTRA receivers operating at the first or second adjacent RF channel.

6.6.2.2.4 Method of test

6.6.2.2.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the ALCR requirements shall be tested with the general test set up specified in section 6.6.2.2.4.1.2 and also with the special test set up for 16QAM capable BS specified in section 6.6.2.2.4.1.3.

6.6.2.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T with multiple carriers if supported; see subclause 5.3.

6.6.2.2.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.25.

Table 6.25: Parameters of the BS transmitted signal for ACLR testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	Real life (sufficient irregular)

6.6.2.2.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.25A.

Table 6.25A: Parameters of the BS transmitted signal for ACLR testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.2.2.4.1.31,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.25B.

Table 6.25B: Parameters of the BS transmitted signal for ACLR testing for 1,28 Mcps TDD- 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each time slot under test~~active TS~~	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-PDSCH	real life (sufficient irregular)
Spreading factor	16

6.6.2.2.4.2 Procedure

6.6.2.2.4.2.1 3,84 Mcps TDD option

1) Measure the RRC filtered mean power centered on the lowest assigned channel frequency over the 2464 active chips of the even time slots TS i (this excludes the guard period).

2) Average over TBD time slots.

3) Measure the RRC filtered mean power at the first lower adjacent RF channel (center frequency 5 MHz below the lowest assigned channel frequency of the transmitted signal) over the useful part of the burst within the even time slots TS i (this excludes the guard period).

4) Average over TBD time slots.

5) Calculate the ACLR by the ratio

ACLR = average acc. to (2) / average interference power acc. to (4).

6) Repeat steps (3), (4) and (5) for the second lower adjacent RF channel (center frequency 10 MHz below the lowest assigned channel frequency of the transmitted signal).

7) In case of a multi-carrier Bs, repeat steps (1) and (2) for the highest assigned channel frequency. Otherwise, use the result obtained in step (2) above for further calculation in step (10).

8) Measure the RRC filtered mean power at the first higher adjacent RF channel (center frequency 5 MHz above the highest assigned channel frequency of the transmitted signal) over the useful part of the burst within the even time slots TS i (this excludes the guard period).

9) Average over TBD time slots.

10) Calculate the ACLR by the ratio

ACLR = average power acc. to (7) / average interference power acc. to (9).

11) Repeat steps (8) to (10) for the second upper adjacent RF channel (center frequency 10 MHz above the highest assigned channel frequency of the transmitted signal).

6.6.2.2.4.2.2 1,28 Mcps TDD option

1) Measure the RRC filtered mean power centered on the lowest assigned channel frequency over the 848 active chips of the transmit time slots TS i (this excludes the guard period).

2) Average over TBD time slots.

3) Measure the RRC filtered mean power at the first lower adjacent RF channel (center frequency 1,6 MHz below the assigned channel frequency of the transmitted signal) over the useful part of the burst within the transmit time slots TS i (this excludes the guard period).

4) Average over TBD time slots.

5) Calculate the ACLR by the ratio:

ACLR = average power acc. to (2) / average interference power acc. to (4).

6) Repeat steps (3), (4) and (5) for the second lower adjacent RF channel (center frequency 3,2 MHz below the lowest assigned channel frequency of the transmitted signal) and also for the first and second upper adjacent RF channel (center frequency 1,6 MHz and 3,2 MHz above the assigned channel frequency of the transmitted signal, respectively).

7) In case of a multi-carrier BS, repeat steps (1) and 2 for the highest assigned channel frequency. Otherwise, use the result obtained in step (2) above for further calculation in step (10).

8) Measure the RRC filtered mean power at the first higher adjacent RF channel (center frequency 1,6 MHz above the highest assigned channel frequency of the transmitted signal) over the useful part of the burst within the transmit time slots TS i (this excludes the guard period).

9) Average over TBD time slots.

10) Calculate the ACLR by the ratio

ACLR = average power acc. to (7) / average interference power acc. to (9).

11) Repeat steps (8) to (10) for the second upper adjacent RF channel (center frequency 3,2 MHz above the highest assigned channel frequency of the transmitted signal).

6.6.2.2.4.2.3 1,28 Mcps TDD option – 16QAM capable BS

The same procedure specified in 6.6.2.2.4.2.2 applies to 1,28 Mcps TDD option BS supporting 16QAM.

6.6.2.2.5 Test Requirements

NOTE: If the Test Requirements below differ from the Minimum Requirements, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

6.6.2.2.5.1 3,84 Mcps TDD option

The ACLR calculated in steps (5) and (10) of subclause 6.6.2.2.4.2.1 shall be equal or greater than the limits given in table 6.26. In case the equipment is tested against the requirements defined for operation in the same geographic area or co-sited with unsynchronised TDD or FDD on adjacent channels, the adjacent channel leakage power measured according to steps (4) and (9) of subclause 6.6.2.2.4.2.1 shall not exceed the maximum levels specified in table 6.27, 6.27A, 6.28 or 6.28A, respectively.

Table 6.26: BS ACLR Test Requirements

BS adjacent channel offset below the first or above the last carrier frequency used	ACLR limit
5 MHz	44,2 dB
10 MHz	54,2 dB

Table 6.27: Adjacent channel leakage power Test Requirements for operation in the same geographic area with unsynchronised TDD on adjacent channels

BS Class	BS adjacent channel offset below the first or above the last carrier frequency used	Maximum Level	Measurement Bandwidth
Wide Area BS	5 MHz	-25 dBm	3,84 MHz
Wide Area BS	10 MHz	-25 dBm	3,84 MHz
Local Area BS	5 MHz	-15,2 dBm	3,84 MHz
Local Area BS	10 MHz	-25,2 dBm	3,84 MHz

Table 6.27A: Adjacent channel leakage power Test Requirements for operation in the same geographic area with FDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 5 MHz	-[36 dBm – TT]	3,84 MHz
Wide Area BS	± 10 MHz	-32 dBm	3,84 MHz
Local Area BS	± 5 MHz	-22,2 dBm	3,84 MHz
Local Area BS	± 10 MHz	-32,2 dBm	3,84 MHz

Table 6.28: Adjacent channel leakage power Test Requirements in case of co-siting with unsynchronised TDD on adjacent channels

BS Class	BS adjacent channel offset below the first or above the last carrier frequency used	Maximum Level	Measurement Bandwidth
Wide Area BS	5 MHz	-[73 dBm - TT]	3,84 MHz
Wide Area BS	10 MHz	-[73 dBm - TT]	3,84 MHz
Local Area BS	5 MHz	-30 dBm	3,84 MHz
Local Area BS	10 MHz	-30 dBm	3,84 MHz

Table 6.28A: Adjacent channel leakage power Test Requirements in case of co-siting with FDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 5 MHz	-80 dBm	3,84 MHz
Wide Area BS	± 10 MHz	-80 dBm	3,84 MHz

6.6.2.2.5.2 1,28 Mcps TDD option

The ACLR calculated in steps (5) and (10) of subclause 6.6.2.2.4.2.2 shall be equal or greater than the limits given in table 6.26A. In case the equipment is tested against the requirements defined for operation in the same geographic area or co-sited with unsynchronised TDD or FDD on adjacent channels, the adjacent channel leakage power measured

according to steps (3) and (4) of subclause 6.6.2.2.4.2.2 shall not exceed the maximum levels specified in tables 6.27B, 6.27C, 6.27D, 6.28B, 6.28C or 6.28D, respectively.

Table 6.26A: BS ACLR Test Requirements (1,28 Mcps option)

BS adjacent channel offset below the first or above the last carrier frequency used	ACLR limit
1,6 MHz	39.2 dB
3,2 MHz	44.2 dB

Table 6.27B: Adjacent channel leakage power Test Requirements for operation in the same geographic area with unsynchronised 1,28 Mcps TDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 1,6 MHz	-28 dBm	1,28 MHz
Wide Area BS	± 3,2 MHz	-28 dBm	1,28 MHz
Local Area BS	± 1,6 MHz	-15,2 dBm	1,28 MHz
Local Area BS	± 3,2 MHz	-15,2 dBm	1,28 MHz

Table 6.27C: Adjacent channel leakage power Test Requirements for operation in the same geographic area with unsynchronised TDD on an adjacent channel

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 3,4 MHz	-28 dBm	3,84 MHz
Local Area BS	± 3,4 MHz	-15,2 dBm	3,84 MHz

Table 6.27D: Adjacent channel leakage power Test Requirements for operation in the same geographic area with FDD on an adjacent channel

BS Class	Center Frequency for Measurement	Maximum Level	Measurement Bandwidth
Wide Area BS	1922,6 MHz	-32 dBm	3,84 MHz
Local Area BS	1922,6 MHz	-22,2 dBm	3,84 MHz

Table 6.28B: Adjacent channel leakage power Test Requirements in case of co-siting with unsynchronised 1,28 Mcps TDD on adjacent channels

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 1,6 MHz	-[73 dBm – TT]	1,28 MHz
Wide Area BS	± 3,2 MHz	-[73 dBm – TT]	1,28 MHz
Local Area BS	± 1,6 MHz	-33 dBm	1,28 MHz
Local Area BS	± 3,2 MHz	-33 dBm	1,28 MHz

Table 6.28C: Adjacent channel leakage power Test Requirements for operation in the same geographic area with unsynchronised TDD on an adjacent channel

BS Class	BS Adjacent Channel Offset	Maximum Level	Measurement Bandwidth
Wide Area BS	± 3,4 MHz	-[73 dBm – TT]	3,84 MHz
Local Area BS	± 3,4 MHz	-30 dBm	3,84 MHz

Table 6.28D: Adjacent channel leakage power Test Requirements in case of co-siting with UTRA FDD on an adjacent channel

BS Class	Center Frequency for Measurement	Maximum Level	Measurement Bandwidth
Wide Area BS	1922,6 MHz	-[80 dBm – TT]	3,84 MHz

6.6.2.2.5.3 1,28 Mcps TDD option- 16QAM capable BS

The same test requirements specified in section 6.6.2.2.5.2 apply to 1,28 Mcps TDD option BS supporting 16QAM.

6.6.3 Spurious emissions

6.6.3.1 Definition and applicability

Spurious emissions are emissions which are caused by unwanted transmitter effects such as harmonics emission, parasitic emission, intermodulation products and frequency conversion products, but exclude out of band emissions. This is measured at the base station RF output port.

The requirements shall apply whatever the type of transmitter considered (single carrier or multiple carrier). It applies for all transmission modes foreseen by the manufacturer's specification.

For 3.84 Mcps TDD option, either requirement applies at frequencies within the specified frequency ranges which are more than 12,5 MHz under the first carrier frequency used or more than 12,5 MHz above the last carrier frequency used.

For 1,28 Mcps TDD option, either requirement applies at frequencies within the specified frequency ranges which are more than 4 MHz under the first carrier frequency used or more than 4 MHz above the last carrier frequency used.

Unless otherwise stated, all requirements are measured as mean power.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS, with the exception of the requirements which may be applied for co-existence with UTRA FDD; in this case, different requirements shall apply to Wide Area BS and Local Area BS.

6.6.3.2 Minimum Requirements

6.6.3.2.1 Mandatory requirements

The requirements of either subclause 6.6.3.2.1.1 or subclause 6.6.3.2.1.2 shall apply.

6.6.3.2.1.1 Spurious emissions (Category A)

The following requirements shall be met in cases where Category A limits for spurious emissions, as defined in ITU-R Recommendation SM.329-8 [6], are applied.

6.6.3.2.1.1.1 3,84 Mcps TDD option

The power of any spurious emission shall not exceed the maximum level given in Table 6.29.

Table 6.29: BS Mandatory spurious emissions limits, Category A

Band	Maximum level	Measurement bandwidth	Note
9 kHz – 150 kHz	-13 dBm	1 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
150 kHz – 30 MHz		10 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
30 MHz – 1 GHz		100 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
1 GHz – 12,75 GHz		1 MHz	Upper frequency as in ITU-R SM.329-8, s2.5 table 1

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.1.1.1.1.

6.6.3.2.1.1.2 1,28 Mcps TDD option

The power of any spurious emission shall not exceed the maximum level given in Table 6.29A.

Table 6.29A: BS Mandatory spurious emissions limits, Category A

Band	Maximum level	Measurement bandwidth	Note
9 kHz – 150 kHz	-13 dBm	1 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
150 kHz – 30 MHz		10 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
30 MHz – 1 GHz		100 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
1 GHz – 12,75 GHz		1 MHz	Upper frequency as in ITU-R SM.329-8, s2.5 table 1

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.1.1.1.2.

6.6.3.2.1.2 Spurious emissions (Category B)

The following requirements shall be met in cases where Category B limits for spurious emissions, as defined in ITU-R Recommendation SM.329-8 [6], are applied.

6.6.3.2.1.2.1 3,84 Mcps TDD option

The power of any spurious emission shall not exceed the maximum levels given in Table 6.30.

Table 6.30: BS Mandatory spurious emissions limits, Category B

Band	Maximum level	Measurement bandwidth	Note
9 kHz – 150 kHz	-36 dBm	1 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
150 kHz – 30 MHz	-36 dBm	10 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
30 MHz – 1 GHz	-36 dBm	100 kHz	Bandwidth as in ITU-R SM.329-8, s4.1
1 GHz – Fc1 - 60 MHz or Fl - 10 MHz *whichever is the higher*	-30 dBm	1 MHz	Bandwidth as in ITU-R SM.329-8, s4.1
Fc1 - 60 MHz or Fl - 10 MHz *whichever is the higher* – Fc1 - 50 MHz or Fl -10 MHz *whichever is the higher*	-25 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.3 and Annex 7
Fc1 - 50 MHz or Fl -10 MHz *whichever is the higher* – Fc2 + 50 MHz or Fu +10 MHz *whichever is the lower*	-15 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.3 and Annex 7
Fc2 + 50 MHz or Fu + 10 MHz *whichever is the lower* – Fc2 + 60 MHz or Fu + 10 MHz *whichever is the lower*	-25 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.3 and Annex 7
Fc2 + 60 MHz or Fu + 10 MHz *whichever is the lower* – 12,75 GHz	-30 dBm	1 MHz	Bandwidth as in ITU-R SM.329-8, s4.1. Upper frequency as in ITU-R SM.329-8, s2.5 table 1

Fc1: Center frequency of emission of the first carrier transmitted by the BS

Fc2: Center frequency of emission of the last carrier transmitted by the BS

Fl : Lower frequency of the band in which TDD operates

Fu : Upper frequency of the band in which TDD operates

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.1.2.1.1.

6.6.3.2.1.2.2 1,28 Mcps TDD option

The power of any spurious emission shall not exceed the maximum levels given in Table 6.30A.

Table 6.30A: BS Mandatory spurious emissions limits, Category B for 1,28 Mcps TDD

Band	Maximum Level	Measurement Bandwidth	Note
9kHz – 150kHz	-36 dBm	1 kHz	Bandwidth as in ITU SM.329-8, s4.1
150kHz – 30MHz	- 36 dBm	10 kHz	Bandwidth as in ITU SM.329-8, s4.1
30MHz – 1GHz	-36 dBm	100 kHz	Bandwidth as in ITU SM.329-8, s4.1
1GHz ↔ Fc1-19,2 MHz or Fl –10 MHz *whichever is the higher*	-30 dBm	1 MHz	Bandwidth as in ITU SM.329-8, s4.1
Fc1 – 19,2 MHz or Fl -10 MHz *whichever is the higher* ↔ Fc1 - 16 MHz or Fl –10 MHz *whichever is the higher*	-25 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.1
Fc1 - 16 MHz or Fl –10 MHz *whichever is the higher* ↔ Fc2 + 16 MHz or Fu +10 MHz *whichever is the lower*	-15 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.1
Fc2 + 16 MHz or Fu + 10 MHz *whichever is the lower* ↔ Fc2 +19,2 MHz or Fu + 10 MHz *whichever is the lower*	-25 dBm	1 MHz	Specification in accordance with ITU-R SM.329-8, s4.1
Fc2 + 19,2 MHz or Fu +10 MHz *whichever is the lower* ↔ 12,75 GHz	-30 dBm	1 MHz	Bandwidth as in ITU-R SM.329-8, s4.1. Upper frequency as in ITU-R SM.329-8, s2.5 table 1

Fc1: Center frequency of emission of the first carrier transmitted by the BS

Fc2: Center frequency of emission of the last carrier transmitted by the BS

Fl : Lower frequency of the band in which TDD operates

Fu : Upper frequency of the band in which TDD operates

The reference for this requirement is TS 25.105 subclause 6.6.3.1.2.1.2.

6.6.3.2.2 Co-existence with GSM

6.6.3.2.2.1 Operation in the same geographic area

This requirement may be applied for the protection of GSM 900 MS in geographic areas in which both GSM 900 and UTRA are deployed.

The power of any spurious emission shall not exceed the maximum level given in Table 6.31.

Table 6.31: BS Spurious emissions limits for BS in geographic coverage area of GSM 900 MS receiver

Band	Maximum level	Measurement bandwidth	Note
921 MHz – 960 MHz	-57 dBm	100 kHz	

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.2.1.1.

6.6.3.2.2.2 Co-located base stations

This requirement may be applied for the protection of GSM 900 BTS receivers when GSM 900 BTS and UTRA BS are co-located.

The power of any spurious emission shall not exceed the maximum level given in table 6.32.

Table 6.32: BS Spurious emissions limits for protection of the GSM 900 BTS receiver

Band	Maximum level	Measurement bandwidth	Note
876 MHz – 915 MHz	–98 dBm	100 kHz	

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.2.2.1.

6.6.3.2.3 Co-existence with DCS 1800

6.6.3.2.3.1 Operation in the same geographic area

This requirement may be applied for the protection of DCS 1800 MS in geographic areas in which both DCS 1800 and UTRA are deployed.

The power of any spurious emission shall not exceed the maximum level given in table 6.33.

Table 6.33: BS Spurious emissions limits for BS in geographic coverage area of DCS 1800 MS receiver

Band	Maximum level	Measurement bandwidth	Note
1805 MHz – 1880 MHz	-47 dBm	100 kHz	

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.3.1.1.

6.6.3.2.3.2 Co-located base stations

This requirement may be applied for the protection of DCS 1800 BTS receivers when DCS 1800 BTS and UTRA BS are co-located.

The power of any spurious emission shall not exceed the maximum level given in table 6.34.

Table 6.34: BS Spurious emissions limits for BS co-located with DCS 1800 BTS

Band	Maximum level	Measurement bandwidth	Note
1710 MHz – 1785 MHz	-98 dBm	100 kHz	

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.3.2.1.

6.6.3.2.4 Co-existence with UTRA FDD

6.6.3.2.4.1 Operation in the same geographic area

This requirement may be applied to geographic areas in which both UTRA TDD and UTRA FDD are deployed.

For TDD base stations which use carrier frequencies within the band 2010 – 2025 MHz the requirements applies at all frequencies within the specified frequency bands in table 6.35. For 3,84 Mcps TDD option base stations which use a carrier frequency within the band 1900-1920 MHz, the requirement applies at frequencies within the specified frequency range which are more than 12,5 MHz above the last carrier used in the frequency band 1900-1920 MHz. For 1,28 Mcps TDD option base stations which use carrier frequencies within the band 1900-1920 MHz, the requirement applies at frequencies within the specified frequency range which are more than 4 MHz above the last carrier used in the frequency band 1900-1920 MHz.

The power of any spurious emission shall not exceed the maximum level given in table 6.35.

Table 6.35: BS Spurious emissions limits for BS in geographic coverage area of UTRA FDD

BS Class	Band	Maximum Level	Measurement Bandwidth	Note
Wide Area BS	1920 – 1980 MHz	-43 dBm (*)	3,84 MHz	
Wide Area BS	2110 – 2170 MHz	-52 dBm	1 MHz	
Local Area BS	1920 – 1980 MHz	-40 dBm (*)	3,84 MHz	
Local Area BS	2110 – 2170 MHz	-52 dBm	1 MHz	
Note *: For 3,84 Mcps TDD option base stations, the requirement shall be measured with the lowest center frequency of measurement at 1922,6 MHz or 15 MHz above the last TDD carrier used, whichever is higher. For 1,28 Mcps TDD option base stations, the requirement shall be measured with the lowest center frequency of measurement at 1922,6 MHz or 6,6 MHz above the last TDD carrier used, whichever is higher.				

NOTE: The requirements for Wide Area BS in Table 6.35 are based on a coupling loss of 67 dB between the TDD and FDD base stations. The requirements for Local Area BS in Table 6.35 are based on a coupling loss of 70 dB between TDD and FDD Wide Area base stations. The scenarios leading to these requirements are addressed in TR 25.942 [9].

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.4.1.1.

6.6.3.2.4.2 Co-located base stations

This requirement may be applied for the protection of UTRA FDD BS receivers when UTRA TDD BS and UTRA FDD BS are co-located.

For TDD base stations which use carrier frequencies within the band 2010 – 2025 MHz the requirements applies at all frequencies within the specified frequency bands in table 6.36. For 3,84 Mcps TDD option base stations which use a carrier frequency within the band 1900-1920 MHz, the requirement applies at frequencies within the specified frequency range which are more than 12,5 MHz above the last carrier used in the frequency band 1900-1920 MHz. For 1,28 Mcps TDD option base stations which use carrier frequencies within the band 1900-1920 MHz, the requirement applies at frequencies within the specified frequency range which are more than 4 MHz above the last carrier used in the frequency band 1900-1920 MHz.

The power of any spurious emission shall not exceed the maximum level given in table 6.36.

Table 6.36: BS Spurious emissions limits for BS co-located with UTRA FDD

BS Class	Band	Maximum Level	Measurement Bandwidth	Note
Wide Area BS	1920 – 1980 MHz	-80 dBm (*)	3,84 MHz	
Wide Area BS	2110 – 2170 MHz	-52 dBm	1 MHz	
Note *: For 3,84 Mcps TDD option base stations, the requirement shall be measured with the lowest center frequency of measurement at 1922,6 MHz or 15 MHz above the last TDD carrier used, whichever is higher. For 1,28 Mcps TDD option base stations, the requirement shall be measured with the lowest center frequency of measurement at 1922,6 MHz or 6,6 MHz above the last TDD carrier used, whichever is higher.				

NOTE: The requirements in table 6.36 are based on a minimum coupling loss of 30 dB between base stations. The co-location of different base station classes is not considered. A co-location requirement for the Local Area TDD BS is intended to be part of a later release.

The normative reference for this requirement is TS 25.105 [1] subclause 6.6.3.4.2.1.

6.6.3.3 Test purpose

6.6.3.3.1 3,84 Mcps TDD option

The test purpose is to verify the ability of the BS to limit the interference caused by unwanted transmitter effects to other systems operating at frequencies which are more than 12,5 MHz away from of the UTRA band used.

6.6.3.3.2 1,28 Mcps TDD option

The test purpose is to verify the ability of the BS to limit the interference caused by unwanted transmitter effects to other systems operating at frequencies which are more than 4 MHz away from of the UTRA band used.

6.6.3.4 Method of test

6.6.3.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the spurious requirements shall be tested with the general test set up specified in section 6.6.3.4.1.2 and also with the special test set up for 16QAM capable BS specified in section 6.6.3.4.1.3.

6.6.3.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T with multiple carriers if supported; see subclause 5.3.

6.6.3.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.37.

Table 6.37: Parameters of the BS transmitted signal for spurious emissions testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.3.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.37A.

Table 6.37A: Parameters of the BS transmitted signal for spurious emissions testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.6.3.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.37B.

Table 6.37B: Parameters of the BS transmitted signal for spurious emissions testing for 1,28 Mcps TDD – 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each time slot under test~~active TS~~	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-PDSCH	real life (sufficient irregular)
Spreading factor	16

6.6.3.4.2 Procedure

Measure the power of the spurious emissions by applying measurement filters with bandwidths as specified in the relevant tables of subclause 6.6.3.2. The characteristic of the filters shall be approximately Gaussian (typical spectrum

analyzer filters). The center frequency of the filter shall be stepped in contiguous steps over the frequency bands as given in the tables. The step width shall be equal to the respective measurement bandwidth. The time duration of each step shall be sufficiently long to capture one active time slot.

6.6.3.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The spurious emissions measured according to subclause 6.6.3.4.2 shall not exceed the limits specified in the relevant tables of 6.6.3.2.

For 1,28 Mcps TDD BS supporting 16QAM, the measured spurious emissions shall not exceed the limits specified for 1,28 Mcps TDD option in section 6.6.3.2.

6.7 Transmit intermodulation

6.7.1 Definition and applicability

The transmit intermodulation performance is a measure of the capability of the transmitter to inhibit the generation of signals in its non linear elements caused by presence of the wanted signal and an interfering signal reaching the transmitter via the antenna.

The transmit intermodulation level is the power of the intermodulation products when a WCDMA modulated interference signal is injected into the antenna connector at a mean power level of 30 dB lower than that of the mean power of the subject signal.

The requirements are applicable for a single carrier.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.7.1.1 3,84 Mcps TDD option

The carrier frequency of the interference signal shall be ±5 MHz, ±10 MHz and ±15 MHz offset from the subject signal carrier frequency, but excluding interference carrier frequencies outside of the UTRA frequency bands specified in 4.2a, 4.2b or 4.2c, respectively.

6.7.1.2 1,28 Mcps TDD option

The carrier frequency of the interference signal shall be ±1,6 MHz, ±3,2 MHz and ±4,8 MHz offset from the subject signal carrier frequency, but excluding interference carrier frequencies outside of the UTRA frequency bands specified in 4.2a, 4.2b or 4.2c, respectively.

6.7.2 Minimum Requirements

The transmit intermodulation level shall not exceed the out of band or the spurious emission requirements of subclause 6.6.2 and 6.6.3, respectively.

The normative reference for this requirement is TS 25.105 [1] subclause 6.7.1.

6.7.3 Test purpose

The test purpose is to verify the ability of the BS transmitter to restrict the generation of intermodulation products in its non linear elements caused by presence of the wanted signal and an interfering signal reaching the transmitter via the antenna to below specified levels.

6.7.4 Method of test

6.7.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the transmit intermodulation requirements shall be tested with the general test set up specified in section 6.7.4.1.2 and also with the special test set up for 16QAM capable BS specified in section 6.7.4.1.3.

6.7.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.7.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment, the BS under test and the WCDMA signal generator as shown in figure 6.2.

(2) Set the parameters of the BS transmitted signal according to table 6.38.

(3) Configure the WCDMA signal generator to produce an interference signal with a mean power level according to subclause 6.7.5. The interference signal shall be like-modulated as the BS transmitted signal, and the active time slots of both signals shall be synchronized. The carrier frequency of the interference signal shall be ±5 MHz, ±10 MHz and ±15 MHz offset from the carrier frequency of the wanted signal, but excluding interference frequencies outside of the UTRA frequency bands specified in 4.2a, 4.2b or 4.2c, respectively.

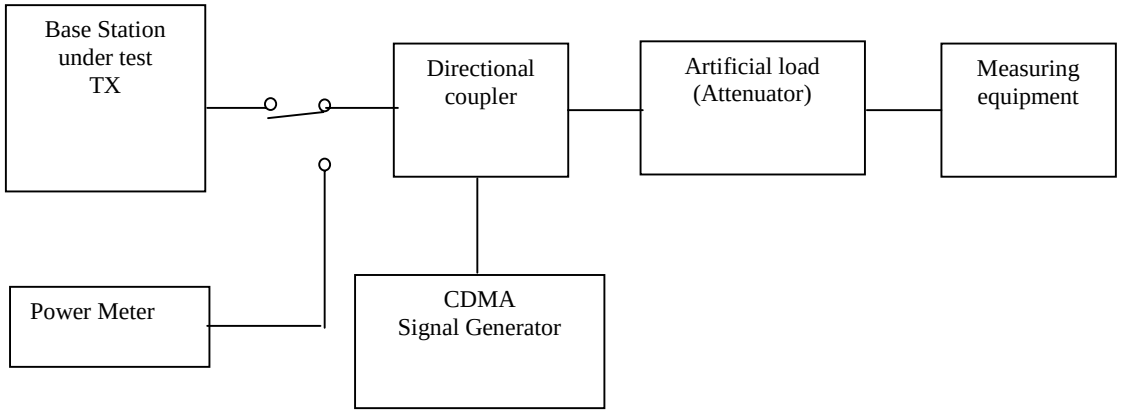

Figure 6.2: Measuring setup for Base Station transmit intermodulation testing

Table 6.38: Parameters of the BS transmitted signal for transmit intermodulation testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is odd; receive, if i is even.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each each time slot under testactive TS	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.7.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment, the BS under test and the WCDMA signal generator as shown in figure 6.2A.

(2) Set the parameters of the BS transmitted signal according to table 6.38A.

(3) Configure the WCDMA signal generator to produce an interference signal with a mean power level according to subclause 6.7.5. The interference signal shall be like-modulated as the BS transmitted signal, and the active time slots of both signals shall be synchronized. The carrier frequency of the interference signal shall be ±1,6 MHz, ±3,2 MHz and ±4,8 MHz offset from the carrier frequency of the wanted signal, but excluding interference frequencies outside of the UTRA frequency bands specified in 4.2a, 4.2b or 4.2c, respectively.

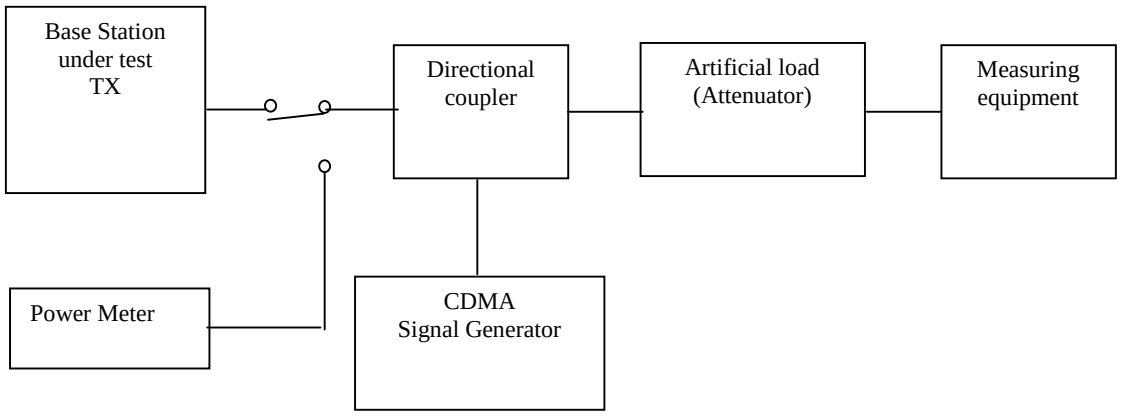

Figure 6.2A: Measuring set up for Base Station transmit intermodulation testing

Table 6.38A: Parameters of the BS transmitted signal for transmit intermodulation testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; I = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

6.7.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment, the BS under test and the WCDMA signal generator as shown in figure 6.2B.

(2) Set the parameters of the BS transmitted signal according to table 6.38B.

(3) Configure the WCDMA signal generator to produce an interference signal with a mean power level according to subclause 6.7.5. The interference signal shall be like-modulated as the BS transmitted signal, and the active time slots of both signals shall be synchronized. The carrier frequency of the interference signal shall be ±1,6 MHz, ±3,2 MHz and ±4,8 MHz offset from the carrier frequency of the wanted signal, but excluding interference frequencies outside of the UTRA frequency bands specified in 4.2a, 4.2b or 4.2c, respectively.

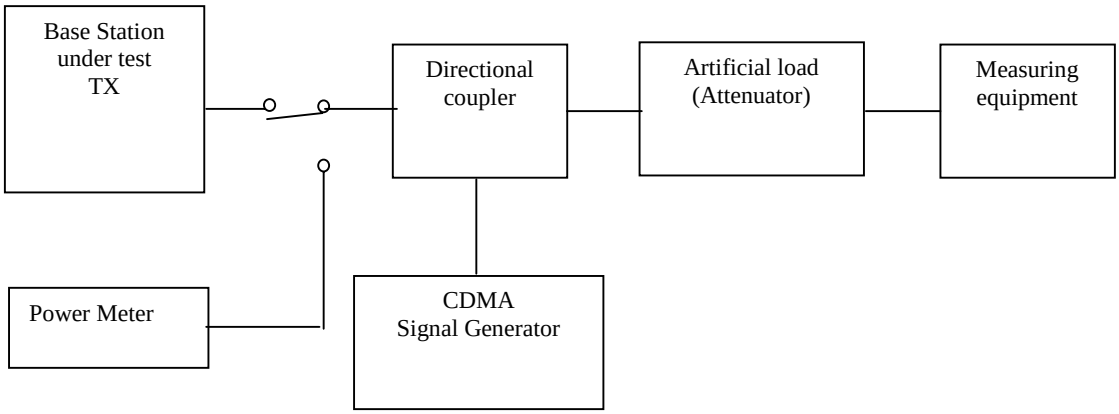

Figure 6.2B: Measuring setup for Base Station transmit intermodulation testing

Table 6.38B: Parameters of the BS transmitted signal for transmit intermodulation testing for 1,28 Mcps TDD- 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each time slot under test~~active TS~~	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-PDSCH	real life (sufficient irregular)
Spreading factor	16

6.7.4.2 Procedure

Apply the test procedures for out of band and spurious emissions as described in 6.6.2 and 6.6.3, respectively, at the frequencies of all third and fifth order intermodulation products. The frequency band occupied by the interference signal are excluded from the measurements.

NOTE: The third order intermodulation products are at frequencies (F1 ± 2F2) and (2F1 ± F2), the fifth order intermodulation products are at frequencies (2F1 ± 3F2), (3F1 ± 2F2), (4F1 ± F2) and (F1 ± 4F2), where F1 represents the frequencies within the bandwidth of the wanted signal and F2 represents the frequencies within the bandwidth of the WCDMA modulated interference signal.

6.7.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The mean power level of the WCDMA modulated interference signal shall be 30 dB below the mean power level of the wanted signal.

At the frequencies of all third and fifth order intermodulation products, the Test Requirements for out of band and spurious emissions as specified in subclauses 6.6.2.1.5 (Spectrum emission mask), 6.6.2.2.5 (ACLR) and 6.6.3.5 (Spurious emissions) shall be met.

6.8 Transmit Modulation

6.8.1 Modulation accuracy

6.8.1.1 Definition and applicability

The Error Vector Magnitude is a measure of the difference between the reference waveform and the measured waveform. This difference is called the error vector. Both waveforms pass through a matched Root Raised Cosine filter with bandwidth corresponding to the considered chip rate and roll-off α =0,22. Both waveforms are then further modified by selecting the frequency, absolute phase, absolute amplitude and chip clock timing so as to minimise the error vector. The EVM result is defined as the square root of the ratio of the mean error vector power to the mean reference power expressed as a %. The measurement interval is one timeslot. The requirement is valid over the total power dynamic range as specified in 25.105 subclause 6.4.3. See Annex C of this specification for further details.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

NOTE: The theoretical modulated waveform shall be calculated on the basis that the transmit pulse shaping filter is a root-raised cosine (RRC) with roll-off α =0,22 in the frequency domain. The impulse response of the chip impulse filter $RC_0(t)$ is

$$RC_0(t) = \frac{\sin\left(\pi \frac{t}{T_C}(1-\alpha)\right) + 4\alpha \frac{t}{T_C}\cos\left(\pi \frac{t}{T_C}(1+\alpha)\right)}{\pi \frac{t}{T_C}\left(1-\left(4\alpha \frac{t}{T_C}\right)^2\right)}$$

Where the roll-off factor α = 0,22 and T_C is the chip duration

6.8.1.2 Minimum Requirements

The error vector magnitude (EVM) shall not exceed 12,5 %. The requirement is valid over the total power dynamic range as specified in subclause 6.4.3 of TS 25.105.

The normative reference for this requirement is TS 25.105 [1] subclause 6.8.2.1.

6.8.1.3 Test purpose

The test purpose is to verify the ability of the BS transmitter to generate a sufficient precise waveform and thus to enable the UE receiver to achieve the specified error performance.

6.8.1.4 Method of test

6.8.1.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the EVM requirements shall be tested with the general test set up specified in section 6.8.1.4.1.2 and also with the special test set up for 16QAM capable base station specified in section 6.8.1.4.1.2.

6.8.1.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.8.1.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39.

Table 6.39: Parameters of the BS transmitted signal for modulation accuracy testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
Number of DPCH in each time slot under test~~active TS~~	1
BS power setting	PRAT
Data content of DPCH	real life (sufficient irregular)

6.8.1.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39A.

Table 6.39A: Parameters of the BS transmitted signal for modulation accuracy testing for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: Transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
Number of DPCH in each time slot under test~~active TS~~	1
Base station power	maximum, according to manufacturer's declaration
Data content of DPCH	real life (sufficient irregular)

6.8.1.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39B.

Table 6.39B: Parameters of the BS transmitted signal for modulation accuracy testing for 1,28 Mcps TDD - 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each each time slot under test~~active TS~~	1
BS station power	Maximum, according to manufacturer's declaration
Data content of HS-PDSCH	Real life (sufficient irregular)
Spreading factor	16

6.8.1.4.2 Procedure

6.8.1.4.2.1 3,84 Mcps TDD option

(1)Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C.

(2) Set the BS output power to PRAT – 30 dB and repeat step (1) above.

6.8.1.4.2.2 1,28 Mcps TDD option – General procedure

(1) Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C.

(2) Set the BS output power to PRAT – 30 dB and repeat step (1) above.

6.8.1.4.2.3 1,28 Mcps TDD option – Special procedure for 16QAM capable BS

(1) Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C.

6.8.1.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The error vector magnitude (EVM) measured according to subclause 6.8.1.4.2 shall not exceed 12,5 %.

6.8.2 Peak code domain error

6.8.2.1 Definition and applicability

The code domain error is computed by projecting the error vector power onto the code domain at a specific spreading factor. The error power for each code is defined as the ratio to the mean power of the reference waveform expressed in dB. And the Peak Code Domain Error is defined as the maximum value for Code Domain Error. The measurement interval is one timeslot.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.8.2.2 Minimum Requirements

The peak code domain error shall not exceed -28 dB at spreading factor 16.

The normative reference for this requirement is TS 25.105 [1] subclause 6.8.3.1.

6.8.2.3 Test purpose

The test purpose is to verify the ability of the BS transmitter to limit crosstalk among codes and thus to enable the UE receiver to achieve the specified error performance.

6.8.2.4 Method of test

6.8.2.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the PCDE requirement shall be tested with the general test set up specified in section 6.8.2.4.2 and also with the special test set up for 16QAM capable BS specified in section 6.8.2.4.3.

6.8.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.8.2.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40.

Table 6.40: Parameters of the BS transmitted signal

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test.~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40A.

Table 6.40A: Parameters of the BS transmitted signal for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each~~-~~ time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40B.

Table 6.40B: Parameters of the BS transmitted signal for 1,28 Mcps TDD – 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
HS-PDSCH modulation	16QAM
BS output power setting	PRAT
Number of HS-PDSCH in each time slot under test~~active TS~~	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-DSCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.2 Procedure

Measure the peak code domain error by applying the global in-channel Tx test method described in Annex C.

6.8.2.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The peak code domain error measured according to subclause 6.8.2.4.2 shall not exceed –27 dB.

---NEXT SECTION---

7.7 Spurious emissions

7.7.1 Definition and applicability

The spurious emissions power is the power of emissions generated or amplified in a receiver that appear at the BS antenna connector. The requirements apply to all BS with separate Rx and Tx antenna connectors. For BS equipped with only a single antenna connector for both transmitter and receiver, the requirements of subclause 6.6.3 shall apply to this port, and this test need not be performed.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

7.7.2 Minimum Requirements

7.7.2.1 3,84 Mcps TDD option

The power of any spurious emission shall not exceed the values given in table 7.12.

Table 7.12: Receiver spurious emission requirements

Band	Maximum level	Measurement Bandwidth	Note
30 MHz – 1 GHz	-57 dBm	100 kHz	
1 GHz – 1,9 GHz	-47 dBm	1 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS
1,900 – 1,980 GHz	-78 dBm	3,84 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS
1,980 – 2,010 GHz	-47 dBm	1 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS
2,010 – 2,025 GHz	-78 dBm	3,84 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS
2,025 GHz – 12,75 GHz	-47 dBm	1 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS

In addition to the requirements in table 7.12, the co-existence requirements for co-located base stations in subclauses 6.6.3.2.2.2, 6.6.3.2.3.2 and 6.6.3.2.4.2 may also be applied.

The normative reference for this requirement is TS 25.105 [1] subclause 7.7.1.1.

7.7.2.2 1,28 Mcps TDD option

The power of any spurious emission shall not exceed the values given in table 7.12A.

Table 7.12A: Receiver spurious emission requirements for 1,28 Mcps TDD

Band	Maximum level	Measurement Bandwidth	Note
30 MHz – 1 GHz	-57 dBm	100 kHz	
1 GHz – 1.9 GHz and 1.98 GHz – 2.01 GHz	-47 dBm	1 MHz	With the exception of frequencies between 4MHz below the first carrier frequency and 4MHz above the last carrier frequency used by the BS.
1.9 GHz – 1.98 GHz and 2.01 GHz – 2.025 GHz	-83 dBm	1.28 MHz	With the exception of frequencies between 4MHz below the first carrier frequency and 4MHz above the last carrier frequency used by the BS.
2.025 GHz – 12.75 GHz	-47 dBm	1 MHz	With the exception of frequencies between 4MHz below the first carrier frequency and 4MHz above the last carrier frequency used by the BS.

In addition to the requirements in table 7.12A, the co-existence requirements for co-located base stations in subclauses 6.6.3.2.2.2, 6.6.3.2.3.2 and 6.6.3.2.4.2 may also be applied.

The normative reference for this requirement is TS 25.105 [1] subclause 7.7.1.2.

7.7.3 Test purpose

The test purpose is to verify the ability of the BS to limit the interference caused by receiver spurious emissions to other systems.

7.7.4 Method of test

7.7.4.1 Initial conditions

7.7.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: M; see subclause 5.3.

7.7.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of one BS Rx port.

(2) Terminate or disable any other BS Rx port not under test.

(3) Set the BS receiver to operational mode.

(4) Set the BS to transmit a signal with parameters according to table 7.13.

(5) Terminate the Tx port(s).

Table 7.13: Parameters of the transmitted signal for Rx spurious emissions test

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Time slot carrying SCH	TS0
Time slots under test	TS i, i even and non zero
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

7.7.4.1.2 1,28 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of one BS Rx port.

(2) Terminate or disable any other BS Rx port not under test.

(3) Set the BS receiver to operational mode.

(4) Set the BS to transmit a signal with parameters according to table 7.13A.

(5) Terminate the Tx port(s).

Table 7.13A: Parameters of the transmitted signal for Rx spurious emissions test for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slots under test	TS4, TS5 and TS6
BS output power setting	PRAT
Number of DPCH in each time slot under test~~active TS~~	8
Power of each DPCH	1/8 of Base Station output power
Data content of DPCH	real life (sufficient irregular)

7.7.4.2 Procedure

7.7.4.2.1 3,84 Mcps TDD option

(1) Measure the power of the spurious emissions by applying the measuring equipment with the settings as specified in table 7.14. The characteristics of the measurement filter with the bandwidth 3,84 MHz shall be RRC with roll-off α = 0,22. The characteristics of the measurement filters with bandwidths 100 kHz and 1 MHz shall be approximately Gaussian (typical spectrum analyzer filter). The center frequency of the filters shall be stepped in contiguous steps over the frequency bands as specified in table 7.14. The time duration of each step shall be sufficiently long to capture one even (transmit) time slot.

(2) If the BS is equipped with more than one Rx port, interchange the connections of the BS Rx ports and repeat the measurement according to (1).

Table 7.14: Measurement equipment settings

Stepped frequency range	Measurement bandwidth	Step width	Note	Detection mode
30 MHz – 1 GHz	100 kHz	100 kHz		true RMS
1 GHz – 1,900 GHz	1 MHz	1 MHz	With the exception of frequencies between 12,5 MHz below the first carrier frequency and 12,5 MHz above the last carrier frequency used by the BS	
1,900 GHz – 1,980 GHz	3,84 MHz	200 kHz		
1,980 GHz – 2,010 GHz	1 MHz	1 MHz		
2,010 GHz – 2,025 GHz	3,84 MHz	200 kHz		
2,025 GHz – 12,75 GHz	1 MHz	1 MHz		

7.7.4.2.2 1,28 Mcps TDD option

(1) Measure the power of the spurious emissions by applying the measuring equipment with the settings as specified in table 7.14A. The characteristics of the measurement filter with the bandwidth 1,28 MHz shall be RRC with roll-off α = 0,22. The characteristics of the measurement filters with bandwidths 100 kHz and 1 MHz shall be approximately Gaussian (typical spectrum analyzer filter). The center frequency of the filters shall be stepped in contiguous steps over the frequency bands as specified in table 7.14A. The time duration of each step shall be sufficiently long to capture one even (transmit) time slot.

(2) If the BS is equipped with more than one Rx port, interchange the connections of the BS Rx ports and repeat the measurement according to (1).

Table 7.14A: Measurement equipment settings

Stepped frequency range	Measurement bandwidth	Step width	Note	Detection mode
30 MHz – 1 GHz	100 kHz	100 kHz		true RMS
1 GHz – 1,900 GHz	1 MHz	1 MHz	With the exception of frequencies between 4 MHz below the first carrier frequency and 4 MHz above the last carrier frequency used by the BS	
1,900 GHz – 1,980 GHz	1,28 MHz	200 kHz		
1,980 GHz – 2,010 GHz	1 MHz	1 MHz		
2,010 GHz – 2,025 GHz	1,28 MHz	200 kHz		
2,025 GHz – 12,75 GHz	1 MHz	1 MHz		

7.7.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The spurious emissions measured according to subclause 7.7.4.2 shall not exceed the limits specified in subclause 7.7.2.

3GPP TSR RAN WG4 Meeting #24 **R4-021217**

Helsinki, Finland 12 - 16 August 2002

CR-Form-v7

CHANGE REQUEST

⌘ **25.142** **CR** **142** ⌘ **rev** ⌘ Current version: **5.1.0** ⌘

*For **HELP** on using this form, see bottom of this page or look at the pop-up text over the ⌘ symbols.*

Proposed change affects: UICC apps⌘ ☐ ME ☐ Radio Access Network ☒ Core Network ☐

Title:	⌘	Correction of QPSK EVM/PCDE test for 1.28 Mcps TDD option.
Source:	⌘	RAN WG4
Work item code:	⌘	TEI5
Date:	⌘	21/08/2002
Category:	⌘	**F**
Release:	⌘	Rel-5

Use one of the following categories:
F *(correction)*
A *(corresponds to a correction in an earlier release)*
B *(addition of feature),*
C *(functional modification of feature)*
D *(editorial modification)*
Detailed explanations of the above categories can be found in 3GPP TR 21.900.

Use one of the following releases:
2 (GSM Phase 2)
R96 (Release 1996)
R97 (Release 1997)
R98 (Release 1998)
R99 (Release 1999)
Rel-4 (Release 4)
Rel-5 (Release 5)
Rel-6 (Release 6)

Reason for change:	⌘	1-For QPSK signals, EVM is tested at maximum output power and minimum output power with only **1** code for 1,28 Mcps TDD option This does not sufficiently stress the Node B transmitter, which likely has the worst EVM performance when multiple codes are transmitted. 2- Normally the maximum power of the Node B is reached when setting the power to PRAT (rated output power). PRAT is the official denomination but the initial condition for the EVM test for 1,28 Mcps TDD option use a different wording. In all other cases, PRAT is used. An alignment with the correct wording is needed in order to prevent confusion. 3-The minimum output power setting is in contradiction with the core requirement (see CR131 for further explanation). 4- EVM and PCDE test should be performed with the same number of codes. It is proposed to align the number of code in both QPSK tests.
Summary of change:	⌘	1- EVM is tested with **10** codes at maximum output power and **1** code at minimum output power. 2- The wording of the maximum output power setting is corrected. 3- The minimum output power setting is corrected. 4- PCDE is tested with **10** codes.
Consequences if not approved:	⌘	A node B passing the existing test would not be a sufficient indication that it would operate correctly when transmitting several codes.

Clauses affected:	⌘	6.8.1, 6.8.2

		Y	N			
Other specs Affected:	⌘		**X**	Other core specifications	⌘	
			X	Test specifications		
			X	O&M Specifications		
Other comments:	⌘					

How to create CRs using this form:
Comprehensive information and tips about how to create CRs can be found at http://www.3gpp.org/specs/CR.htm. Below is a brief summary:

1) Fill out the above form. The symbols above marked ⌘ contain pop-up help information about the field that they are closest to.

2) Obtain the latest version for the release of the specification to which the change is proposed. Use the MS Word "revision marks" feature (also known as "track changes") when making the changes. All 3GPP specifications can be downloaded from the 3GPP server under ftp://ftp.3gpp.org/specs/ For the latest version, look for the directory name with the latest date e.g. 2001-03 contains the specifications resulting from the March 2001 TSG meetings.

3) With "track changes" disabled, paste the entire CR form (use CTRL-A to select it) into the specification just in front of the clause containing the first piece of changed text. Delete those parts of the specification which are not relevant to the change request.

6.8 Transmit Modulation

6.8.1 Modulation accuracy

6.8.1.1 Definition and applicability

The Error Vector Magnitude is a measure of the difference between the reference waveform and the measured waveform. This difference is called the error vector. Both waveforms pass through a matched Root Raised Cosine filter with bandwidth corresponding to the considered chip rate and roll-off α =0,22. Both waveforms are then further modified by selecting the frequency, absolute phase, absolute amplitude and chip clock timing so as to minimise the error vector. The EVM result is defined as the square root of the ratio of the mean error vector power to the mean reference power expressed as a %. The measurement interval is one timeslot. The requirement is valid over the total power dynamic range as specified in 25.105 subclause 6.4.3. See Annex C of this specification for further details.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

NOTE: The theoretical modulated waveform shall be calculated on the basis that the transmit pulse shaping filter is a root-raised cosine (RRC) with roll-off α =0,22 in the frequency domain. The impulse response of the chip impulse filter $RC_0(t)$ is

$$RC_0(t) = \frac{\sin\left(\pi \frac{t}{T_C}(1-\alpha)\right) + 4\alpha \frac{t}{T_C}\cos\left(\pi \frac{t}{T_C}(1+\alpha)\right)}{\pi \frac{t}{T_C}\left(1-\left(4\alpha \frac{t}{T_C}\right)^2\right)}$$

Where the roll-off factor α = 0,22 and T_C is the chip duration

6.8.1.2 Minimum Requirements

The error vector magnitude (EVM) shall not exceed 12,5 %. The requirement is valid over the total power dynamic range as specified in subclause 6.4.3 of TS 25.105.

The normative reference for this requirement is TS 25.105 [1] subclause 6.8.2.1.

6.8.1.3 Test purpose

The test purpose is to verify the ability of the BS transmitter to generate a sufficient precise waveform and thus to enable the UE receiver to achieve the specified error performance.

6.8.1.4 Method of test

6.8.1.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the EVM requirements shall be tested with the general test set up specified in section 6.8.1.4.1.2 and also with the special test set up for 16QAM capable base station specified in section 6.8.1.4.1.2.

6.8.1.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.8.1.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39.

Table 6.39: Parameters of the BS transmitted signal for modulation accuracy testing

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
Number of DPCH in each active TS	1
BS power setting	PRAT
Data content of DPCH	real life (sufficient irregular)

6.8.1.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39A.

Table 6.39A: Parameters of the BS transmitted signal for modulation accuracy testing at maximum BS output power for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: Transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Number of DPCH in each active TS	10~~1~~
Power of each DPCH	1/10 of Base Station output power
Base station power	PRAT~~maximum, according to manufacturer's declaration~~
Data content of DPCH	real life (sufficient irregular)

6.8.1.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.39B.

Table 6.39B: Parameters of the BS transmitted signal for modulation accuracy testing for 1,28 Mcps TDD - 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, 3, 4, 5, 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
HS-PDSCH modulation	16QAM
Number of HS-PDSCH in each active TS	1
BS station power	Maximum, according to manufacturer's declaration
Data content of HS-PDSCH	Real life (sufficient irregular)
Spreading factor	16

6.8.1.4.2 Procedure

6.8.1.4.2.1 3,84 Mcps TDD option

(1)Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C.

(2) Set the BS output power to PRAT – 30 dB and repeat step (1) above.

6.8.1.4.2.2 1,28 Mcps TDD option – General procedure

(1) Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C with the BS transmitted signal set as described in Table 6.39A.

(2) Set the BS transmitted signal according Table 6.39XX and measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C. ~~Set the BS output power to PRAT – 30 dB and repeat step (1) above.~~

Table 6.39XX: Parameters of the BS transmitted signal for modulation accuracy testing at minimum BS output power for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: Transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
Time slot under test	TS4, TS5 and TS6
Number of DPCH in each time slot under test	1
BS output power setting	Maximum output power – 30 dB
Data content of DPCH	Real life (sufficient irregular)

6.8.1.4.2.3 1,28 Mcps TDD option – Special procedure for 16QAM capable BS

(1) Measure the error vector magnitude (EVM) by applying the global in-channel Tx test method described in Annex C.

6.8.1.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The error vector magnitude (EVM) measured according to subclause 6.8.1.4.2 shall not exceed 12,5 %.

6.8.2 Peak code domain error

6.8.2.1 Definition and applicability

The code domain error is computed by projecting the error vector power onto the code domain at a specific spreading factor. The error power for each code is defined as the ratio to the mean power of the reference waveform expressed in dB. And the Peak Code Domain Error is defined as the maximum value for Code Domain Error. The measurement interval is one timeslot.

The requirements in this subclause shall apply to both Wide Area BS and Local Area BS.

6.8.2.2 Minimum Requirements

The peak code domain error shall not exceed -28 dB at spreading factor 16.

The normative reference for this requirement is TS 25.105 [1] subclause 6.8.3.1.

6.8.2.3 Test purpose

The test purpose is to verify the ability of the BS transmitter to limit crosstalk among codes and thus to enable the UE receiver to achieve the specified error performance.

6.8.2.4 Method of test

6.8.2.4.1 Initial conditions

For 1,28 Mcps BS supporting 16QAM, the PCDE requirement shall be tested with the general test set up specified in section 6.8.2.4.2 and also with the special test set up for 16QAM capable BS specified in section 6.8.2.4.3.

6.8.2.4.1.0 General test conditions

Test environment: normal; see subclause 5.9.1.

RF channels to be tested: B, M and T; see subclause 5.3.

6.8.2.4.1.1 3,84 Mcps TDD option

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40.

Table 6.40: Parameters of the BS transmitted signal

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 14: transmit, if i is even; receive, if i is odd.
BS output power setting	PRAT
Number of DPCH in each active TS	9
Power of each DPCH	1/9 of Base Station output power
Data content of DPCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.1.2 1,28 Mcps TDD option– General test set up

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40A.

Table 6.40A: Parameters of the BS transmitted signal for 1,28 Mcps TDD

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
BS output power setting	PRAT
Number of DPCH in each active TS	10~~8~~
Power of each DPCH	1/10~~8~~ of Base Station output power
Data content of DPCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.1.3 1,28 Mcps TDD option – Special test set up for 16QAM capable BS

This test set up only applies for 16QAM capable BS.

(1) Connect the measuring equipment to the antenna connector of the BS under test.

(2) Set the parameters of the BS transmitted signal according to table 6.40B.

Table 6.40B: Parameters of the BS transmitted signal for 1,28 Mcps TDD – 16QAM capable BS

Parameter	Value/description
TDD Duty Cycle	TS i; i = 0, 1, 2, ..., 6: transmit, if i is 0,4,5,6; receive, if i is 1,2,3.
HS-PDSCH modulation	16QAM
BS output power setting	PRAT
Number of HS-PDSCH in each active TS	8
Power of each HS-PDSCH	1/8 of Base Station output power
Data content of HS-DSCH	real life (sufficient irregular)
Spreading factor	16

6.8.2.4.2 Procedure

Measure the peak code domain error by applying the global in-channel Tx test method described in Annex C.

6.8.2.5 Test Requirements

NOTE: If the Test Requirement below differs from the Minimum Requirement, then the Test Tolerance applied for this test is non-zero. The Test Tolerance for this test is defined in subclause 5.11 and the explanation of how the Minimum Requirement has been relaxed by the Test Tolerance is given in Annex D.

The peak code domain error measured according to subclause 6.8.2.4.2 shall not exceed –27 dB.